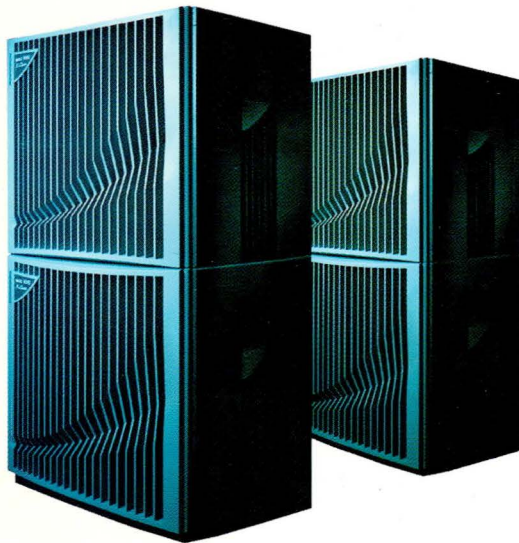
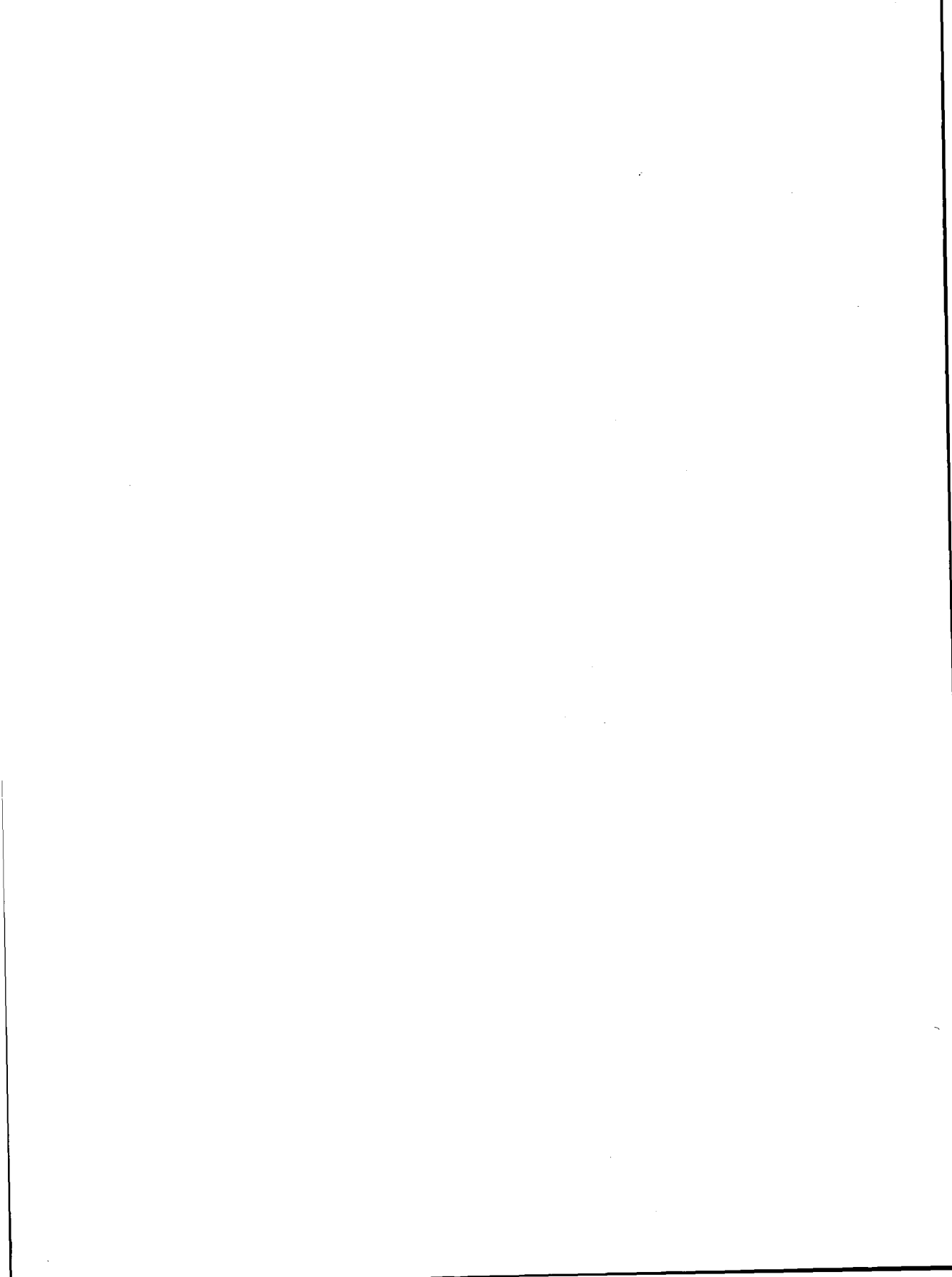


S-Class and
X-Class Servers



Exemplar Diagnostics Guide

First Edition



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Exemplar Diagnostics Guide

S-Class and X-Class Servers

A4716-90002

First Edition

January, 1997

Hewlett-Packard Company
Convex Division
Richardson, Texas
United States of America

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S-Class and X-Class Servers

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Preface

Purpose

The *Exemplar Diagnostics Guide for S-Class and X-Class Servers* documents the diagnostics for these systems. This book is not intended to be a tutorial, but rather a reference for field service and manufacturing personnel.

Using this book

This book has the following eight chapters including:

- Chapter 1, "Introduction," provides an introduction to Exemplar S-Class and X-Class diagnostics. The node Utilities board is discussed in detail.
- Chapter 2, "Configuration management," discusses the `ccmd` and `ccmu` daemons.
- Chapter 3, "Power-On Self Test," describes how POST initializes a hypernode and handles power up errors.
- Chapter 4, "Test controller," describes an EEPROM-based utility that provides the environment for executing the off-line diagnostic tests.
- Chapter 5, "xctest," discusses a graphical front end and a command line interpreter for the test controller that runs on the test station.
- Chapter 6, "mem3000," details the memory test module called `mem3000`.
- Chapter 7, "Utilities," describes several utilities and tools to enhance diagnostic testing.
- Chapter 8, "Excalibur scan test," details a diagnostic utility (`est`) that uses the system scan hardware making it possible to perform connectivity tests and to test gate array internals.

Notational conventions

This section discusses notational conventions used in this book.

Monospace

The monospace font identifies command names, system calls, and data structures and types.

In command and code examples, monospace identifies command output, including error messages

Italic

In paragraph text, *italic* identifies new and important terms and titles of documents.

Bold

The **bold** character format indicates special emphasis.

Notes and cautions

This document presents notes and cautions in the following formats.

Note

A Note highlights supplemental information.

Caution

A Caution highlights information necessary to avoid damage to the system.

Associated documents

Using Exemplar S-Class or X-Class servers may require information not specific to the functionality described in this document.

- *PA-RISC 2.0 Architecture*. This manual contains generic information about the PA-RISC architecture used as a basis for the S-Class and X-Class servers.
- *Exemplar Architecture: S-Class and X-Class Servers*, part number A4716-90001, provides details of these systems.

Ordering documents

To order the current edition of these or any other Hewlett-Packard documents, send requests to:

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If you have questions that are not answered in this book, contact the Hewlett-Packard Convex Technical Assistance Center (TAC) at the following locations:

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You can also use the *contact utility*, if you would like to report any problems you may have.

This chapter presents an overview of the diagnostic mechanism for S-Class and X-Class servers.

Utilities board

Diagnostics in S-Class and X-Class servers are centered around the hypernode Utilities board which connects directly to the midplane board. Attached to the Utilities board are the core logic bus, environmental sensors, and other test points. The board also interfaces to the hypernode liquid crystal display (LCD), a test terminal (via an ethernet connection), and other external devices. The terminal is connected via these links to configure the hypernode and run diagnostics.

Figure 1 shows the Utilities board functional layout.

The Utilities board is comprised of the following hardware components:

- Core logic—Contains initialization and booting firmware.
- Monitor Utilities Chip (MUC)—Collects environmental interrupts.
- Processor Utilities Chip (PUC)—Interfaces to the core logic bus.
- Power-On circuit—Controls powering up the entire hypernode.
- JTAG (Joint Test Action Group) interface—Supports a test station and a mechanism to fanout JTAG to all the boards in a hypernode. It is used only for testing.

The MUC latches hypernode interrupts, most of which are from environmental sensors located throughout the hypernode. The MUC and the power-on circuit together control system power-up. The MUC interfaces to a light-emitting diode (LED) diagnostic display through the power-on circuit.

The PUC provides the core logic with an interface to the core logic bus. There are actually two buses, each one connects up to four Processor Agent Controllers (PACs). The PUC communicates to the PACs using data packets.

S-Class and X-Class servers use a test method called scanning to test boards and other hardware units. With the test station connected to the ethernet between hypernodes, you can scan any hypernode in a multiple hypernode system without moving connectors.

The JTAG interface contains a microprocessor to capture packets from the ethernet and apply them to the JTAG test bus controller or to take scan information from the JTAG test bus controller and send it out on the ethernet. The test station can also read and write every CSR in the hypernode.

The S-Class and X-Class systems test station is an HP-712 workstation that attaches to the system via ethernet. It is required for installing a multiple hypernode system and to service single and multiple hypernode systems. A system will boot and operate without a test station, and failure of the test station will not cause interruption of the system.

Progress/status messages are also displayed to the LCD during the boot process.

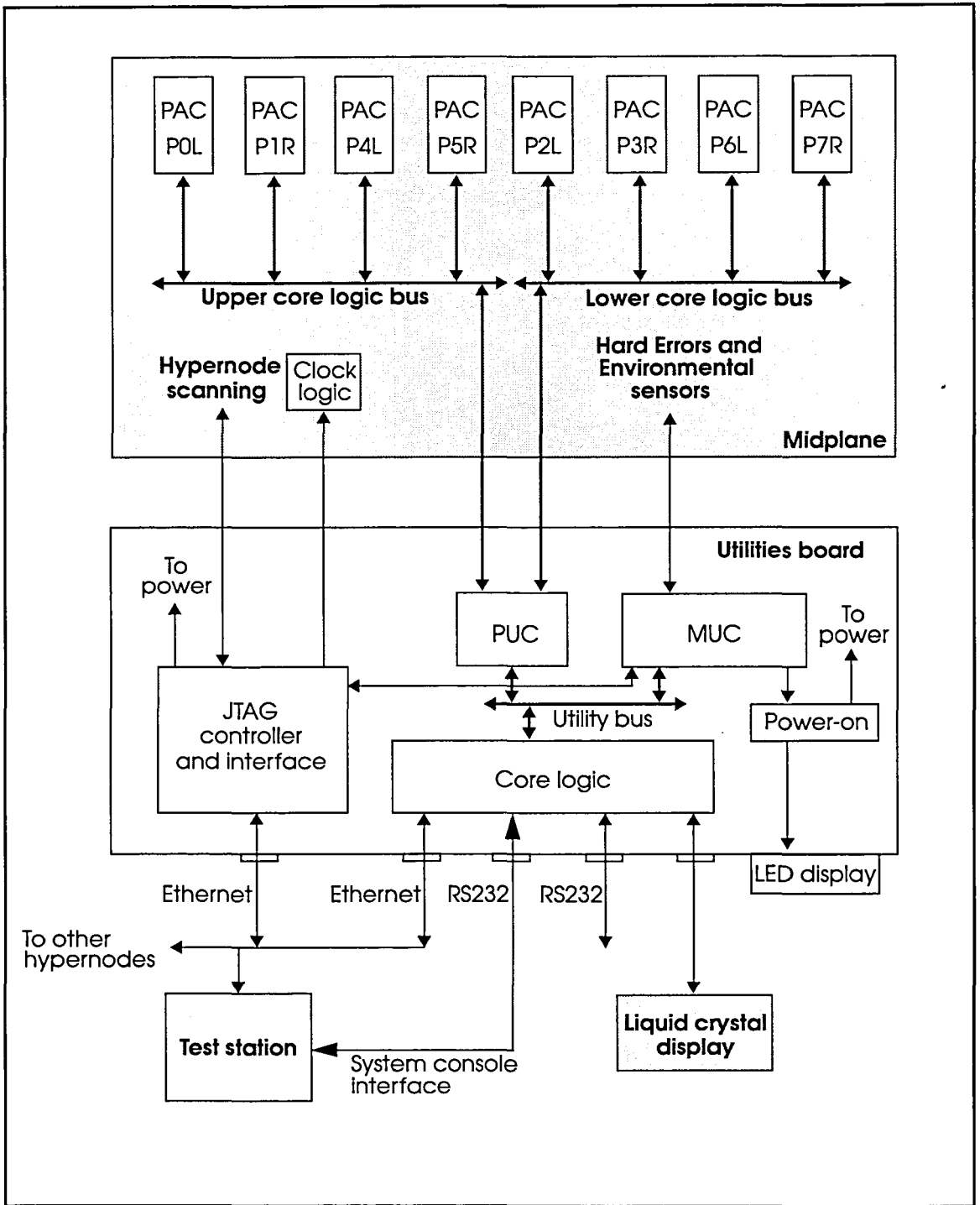


Figure 1 Hypernode Utilities board

Core logic

The core logic contains initialization and booting firmware and is described in the following sections.

Flash memory

The core logic contains nonvolatile storage for processor-dependent code. This code consists of primary loader code, the Open Boot PROM (OBP) code, and power-on self test software. This EEPROM memory is 4 MBytes, configured as 512-Kbyte addresses by 32 data bits with only 32-bit read and write accesses allowed. It is writable by the processors for field upgrades and can be written when the PUC is *scanned*.

Nonvolatile static RAM

The core logic section contains a nonvolatile battery-backed RAM (NVRAM). The NVRAM is used to write system log information and store configuration information. This RAM is byte addressable and can be accessed even after power failures occur.

DUART

The utilities logic contains a Dual Universal Asynchronous Receiver-Transmitter (DUART). One port, configured as a basic RS232 port, provides an interface to the simplest core system functions. With this interface, you can connect a terminal as a local console to analyze problems, reconfigure the system, or provide other user access. The parallel port of the DUART drives the LCD. The second RS232 port can be used for a modem for field service.

RAM

RAM is needed to support the simple core system functions. When the hypernode powers up, the processors operate out of this RAM. They run self test software to test and configure the rest of the hypernode. Once the system is fully configured, the processors execute out of main memory. The RAM is byte addressable and is 128 KBytes, configured as 32K addresses by 32 data bits (with parity).

Console ethernet

The ethernet I/O port connects to the test station over LAN1.

LEDs and LCD

Light Emitting Diodes display environmental information, such as the source of an environmental error that caused the Utilities board to power down the hypernode.

The LCD is driven by one of the processors via the Utilities board. A large amount of information can be displayed on the LCD. The core logic drives the LCD via the parallel port on the DUART.

COP interface

COP chips (serial EEPROMs) are located on the major boards with information such as serial number, error history, configuration information, and so on. The MUC connects to the COP bus selector (CBS) chip on the midplane and allows the system to read any COP in a hypernode.

PUC

The PUC provides the Utilities board a means to apply interrupts and error messages to the processors and to receive control messages from the processors. It has two 18-bit, bidirectional buses. Each interface connects up to four PACs. The PUC provides core logic bus arbitration for the sixteen hypernode processors.

Through the PUC, the PAC has an interface to the utilities bus on the Utilities board. This bus connects the PUC, the MUC, and the core logic section together.

MUC and Power-on

The MUC performs all environmental monitoring on the Utilities board. It attaches to the utilities bus so that processors can monitor the hypernode by accessing these CSRs.

The MUC works in conjunction with a hardware section on the Utilities board known as the power-on circuit. This circuit controls powering up the entire hypernode. It is able to operate when the rest of the hypernode is powered off or in some indeterminate state. It drives the environment LED display which is a basic (minimal hardware, no software) indication of what environmental error caused the Utilities board to power down the hypernode.

The test station can also read the environmental LED display using the `pce_util` utility. See the “`pce_util`” section on page 83.

MUC environmental monitoring

The MUC and the power-on circuit monitor the following environmental conditions:

- ASIC installation error sensing
- FPGA configuration and status
- Thermal sensing
- Fan Sensing
- Power failure sensing
- 48-V failure
- 48-V maintenance
- Ambient air temperature sensing
- Power-on

Table 1 Environmental conditions monitored by the MUC and power-on circuit

Condition	Type	Action
ASIC Not Installed OK	Environmental error	Power not turned on, LED indication
FPGA not OK	Environmental error	Power not turned on, LED indication
48-V Fail	Environmental error	Power turned off, LED indication
Midplane power fail	Environmental error	Power turned off, LED indication
Board over temp	Environmental error	Power off in one second, LED indication, Interrupt
Fan not turning	Environmental error	Power off in one second, LED indication, Interrupt
Ambient air hot	Environmental error	Power off in one second, LED indication, interrupt
Other power fail	Environmental error	Power off in one second, LED indication, interrupt
Ambient air warm	Environmental warning	LED indication, interrupt
48-Volt maintenance	Environmental warning	LED indication, interrupt
Hard error	Hard error	LED indication, interrupt

Environmental condition detected by power-on function

The power-on function detects environmental errors (such as ASIC Install or FPGA Not OK) immediately and does not turn on power to the hypernode until the conditions are corrected. It also detects environmental errors such as 48-V Fail while the system is powering up and Midplane Power Fail after the system has

powered up. If a failure is detected in these two cases, the power-on circuit turns off power to the system.

Environmental warnings such as 48-Volt Maint are also detected by the power-on circuit. It applies these to the MUC which then sends an environmental warning interrupt to the hypernode processors.

In all cases, the power-on circuit lights an environmental LED display code. The environmental LED display code is prioritized so that it only displays the highest priority error or warning. See the "LED environmental display" section on page 10 for a list of codes. For more information, use `man LEDs` on the test station.

Environmental conditions detected by MUC

The MUC detects most of the environmental conditions. It samples error conditions during a time period derived from a local 10-Hz clock that drives the power-on circuit. It registers all the environmental error conditions twice and then logically ORs them together. If the conditions persist for 200 mS, the environmental error bit is set, and an environmental error interrupt is sent to the PUC, which sends it on to the processors. The MUC then waits 1.2 seconds and commands the power-on circuit to power down the system.

This same procedure exists for an environmental warning, except that an environmental warning interrupt is sent and the power-on circuit does not power down the system.

The environmental error interrupt and the 1.2 second delay provide the system adequate time to read CSRs to determine the cause of the error, log the condition in NVRAM, and display the condition on the LED. Use the `pce_util` utility to read the LEDs. See the "pce_util" section on page 83.

After the system is powered down, the Utilities board is still powered up, but all outputs are disconnected from the system.

Environmental control

The Utilities board performs the following functions to control the hypernode environment.

Power-on

When the power switch is turned on, the outputs of the 48-volt power supplies become active. Several hundred milliseconds after the Utilities board 5-volt supply reaches an acceptable level, the power-on circuit starts powering up the other DC-to-DC

converters of the hypernode. It does not turn on all converters at the same time. Instead, the converters are powered-on in succession.

The power-on circuit does not power up the hypernode if an ASIC is installed incorrectly (see the "ASIC installation error" section on page 12) or if an FPGA is not configured (see the "FPGA configuration and status" section on page 13). It keeps the system powered up unless an environmental condition occurs that warrants a power-down.

Voltage margining

Voltage margin is divided into four groups to minimize control, but allows all boards that communicate with each other to be margined separately for nominal, upper, and lower voltage.

Clock margining

Parallel ports on the core logic microprocessor select the nominal, upper, or external clock that drives the hypernode.

JTAG interface

The JTAG interface supports a test station and a mechanism to fanout JTAG to all the boards in a hypernode. It is used only for testing.

The JTAG functions are described in the following sections.

Test station interface

The test station can be a PA-RISC based workstation or laptop computer. The interface to the test station is an ethernet AUI port for flexibility in connecting to many workstations and laptops. It is also easily expandable to all the hypernodes in a single wall.

AC test of a hypernode

An AC test is performed by a Test Bus Controller (TBC) scanning in data to all boards in a hypernode and loading an AC Test instruction into all ASICs on one board.

Once all boards have been almost loaded with the AC test instruction and paused, the TBC takes all boards out of pause mode simultaneously causing them all to exit update together and execute the AC test.

The AC test enables clocks inside the ASICs so that they test internal and external paths at the system clock rate. They all execute on the same system clock.

JTAG fanout

The test station interface is thin ethernet. This port is also used for console ethernet. There is one cable that connects to all the hypernodes and to the test station (if it exists) and to whatever device or network that will display the console.

System Displays

The Exemplar S-Class and X-Class servers provide the two displays for status and error reporting: an LCD and LEDs.

Front panel LCD

The front panel is a 20-character by 4-line liquid crystal display as shown in Figure 2.

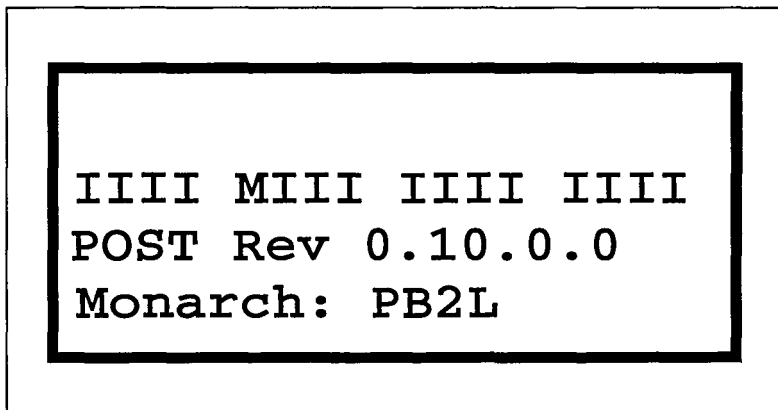


Figure 2 Front panel LCD

When the node key switch is turned on, the LCD will power up but will initially be blank.

POST takes about 20 seconds to start displaying output to the LCD. The following illustrates this output shown in Figure 2:

- First row is blank
- Second row displays the processor status
- Third row displays the revision of POST
- Last row displays which processor is in control
- POST is described in Chapter 3

LED environmental display

Second-level registers in the MUC drive the 6-bit LED display. The MUC prioritizes the environmental errors and warnings, and it passes the information to the power-on circuit. This circuit prioritizes the 6-bit field with its environmental conditions and produces a 7-bit field plus an attention bit (ATTN) that drives the LED display. ATTN is on if there is an environmental warning.

In general, the power-on-detected errors are a higher priority than MUC-detected errors, the lower the error code number, the higher

its priority. Environmental warnings are lower priority than the environmental errors. Table 2 shows the LED display error codes.

Table 2 Environmental LED display

ATTN bit	LED display	Description
1	00	ECUB 3.3-V error (highest priority)
1	01	ASIC Install 0 (ENRB)
1	02	ASIC Install 1 (MEM)
1	03	FPGA not OK
1	04-07	DC OK error (UL, UR, LL, LR)
1	08-11	48-V error, NPSUL fail, PWRUP=0-9
1	12-1B	48-V error, NPSUR failure, PWRUP=0-9
1	1C-25	48-V error, NPSLL failure, PWRUP=0-9
1	26-2F	48-V error, NPSLR failure, PWRUP=0-9
1	30-39	48-V error, no supply failure, PWRUP=0-9
1	3A	48-V yo-yo error
1	3B	ENRB power failure (ENRBPB)
1	3C	Clock failure
1	3D-3F	Not used (3)
1	40-47	MB0-MB7 power failure
1	48-4F	PB0L, PB1R, PB2L, PB3R, PB4L, PB5R, PB6L, PB7R power failure
1	50-57	PB0R, PB1L, PB2R, PB3L, PB4R, PB5L, PB6R, PB7L power failure (possibly switch R and L)
1	58-5B	IOB (LR,LF,RF,RR) power failure
1	5C-61	Fan failure (UR,UM,UL,LR,LM,LL)
1	62	Ambient hot
1	63	Overtemp ENRB
1	64-67	Overtemp quadrant (RL, RU, LL, LU)
1	68	Hard error
1	69	Ambient warm
1	6A-6F	Not used (6)
1	70-73	DC supply maintenance (UL,UR,LL,LR)

Table 2 Environmental LED display—(continued)

ATTN bit	LED display	Description
1	74-7F	Not used (12)
0	00-09	PWRUP state (00=System all powered up), attention LED off

The top of the table is the highest priority, the bottom the lowest. If a higher condition occurs, that one is displayed.

ECUB 3.3-Volt error

This error indicates that the ECUB 3.3-volt power supply has failed, but the 5-volt supply has not.

ASIC installation error

Each ASIC in the hypernode has ASIC Install lines to prevent power-up if an ASIC is installed incorrectly (such as a PAC installed in a RAC's position). If an ASIC is improperly installed, the Utilities board does not power up the system. This condition is not monitored after power up.

DC OK error

When this error is displayed, the power-on circuit did not power up the system, because one or more 48-volt power supplies reported an error. In systems with redundant 48-volt power supplies, this error means that two or more 48-volt supplies reported an error.

48-volt error

If the 48-volt supply has dropped below 42 volts for any reason other than normally turning off the system or an AC failure, then this error is displayed by the power-on circuit. Also, the 48-volt supply that reported the error and the power-up state of the system at the time of the error is displayed.

48-volt yo-yo error

This error indicates that a 48-volt error occurred and the ECUB lost and then later regained power without the machine being turned off. The power-on circuit will display this error and not power on the system, because the 48-volt supply is likely at fault.

Clock failure

If the system clock fails, then the MUC is unable to monitor environmental errors that could possibly damage the system. If the power-on circuit receives no response from the MUC, it powers down the system and displays this error.

FPGA configuration and status

The MUC is programmed by a serial data transfer from EEPROM upon utility board power-up. If the transfer does not complete properly, the MUC cannot configure itself and many environmental conditions cannot be monitored. The power-on circuit monitors both the MUC and PUC and does not power up the system, if they are not configured correctly.

Board over-temperature

On each board in the hypernode, there is one temperature sensor that detects board overheating. The sensors are bussed together into four hypernode quadrants plus the midplane and applied to the MUC.

Fan sensing

Sensors in the four fans determine if the fans are running properly. The MUC waits 12.8 seconds for the fans to spin up after power-up before monitoring them.

Power failure

Because a power failure on a board could cause damage to other boards, a mechanism on each board detects 3.3-Volt failures on each board. Power failures are considered environmental errors, and the system is powered down after they are detected.

Midplane power failure

If the midplane power fails, the power-on circuit powers down the entire hypernode. The Utilities board is still active, but the power-on circuit displays the power failure condition and disables all Utilities board outputs that drive the hypernode. This condition persists until power is cycled on the Utilities board.

48-volt maintenance

There are four 48-volt power supplies; three are required, one is a redundant source. Each sends a signal to the power-on circuit. If any supply fails at any time, the circuit asserts the 48-V maintenance line to the MUC, which reports the environmental

warning to the processors. The power-on circuit displays the “highest priority” 48-volt supply that failed.

Ambient air sensors

The ambient air sensors detect a too warm or too hot condition in the input air stream to the Utilities board (and therefore the entire hypernode). Ambient air too warm is an environmental warning; ambient air too hot is an environmental error that powers down the system.

The temperature set points are set using the ds1620 utility, described in Chapter 7. The digital temperature sensor has nonvolatile storage for the temperature set points. Power-on reset starts the digital temperature sensor without the core logic microprocessor intervening.

The test station allows the user to configure the node. The test station daemon, `ccmd`, is responsible for monitoring the node and reporting back configuration information, error information and general status. Two utilities, `ccmu` and `xconfig`, are each capable of reading or writing configuration information and changing it. OBP can also be used to modify the configuration.

Test station

The test station is required in system bring-up, monitoring, testing, and error logging. It is not required for normal operation of a node.

The node JTAG interface connects to the test station. This communications port remains idle if no test station is connected to it. It receives communications packets and interpret requests and generates responses to them. The hardware on the node can read board information, system configuration, device revisions and environmental conditions. When a test station is present, all of these parameters are read or written by the configuration management tools.

The main tool to initiate communications is the complex configuration management daemon, `ccmd`.

ccmd

The communications configuration manager daemon, `ccmd`, builds configuration information database on the test station. The board names and revisions, the device names and revisions, and the start-up information generated by POST are all read and stored in memory for use by other diagnostic tools.

`ccmd` is typically run automatically from `/etc/inittab` on the test station. If `ccmd` dies, it is restarted if listed in `/etc/inittab`. It can also be started from the command line by entering:

```
ccmd [-d]
```

Very few of the diagnostic utilities can run without the information database created by `ccmd`. The debug option, `-d`, reports on its progress and problems communicating with the node.

`ccmd` is started by `init` on the test station. `init` monitors `ccmd` and respawns it if it ever dies. Once started, `ccmd` becomes a daemon and allocates a block of test station memory to be used as a database for all nodes, boards and devices.

Next, `ccmd` reads the file `/spp/data/complex.info` to determine what complexes, nodes, and JTAG ports are available to communicate with the test station. `ccmd` then broadcasts a command to all JTAG ports to report in. As each node responds with its IP address, `ccmd` sends a request to each node for the node identification number. `ccmd` continues until no new responses are detected.

Once `ccmd` has all valid node numbers and IP addresses, it scans each ring of each node looking for JTAG device IDs. The JTAG IDs contain device and revision information stored in the test station database. The JTAG ID is cross checked in the `/spp/data/part_ids` file to retrieve a complete device description of the part. The file for the part is also in `/spp/data`.

After `ccmd` loads all parts and their descriptions into the database, it reads all board information. Board and device information is cross checked in the file `/spp/data/DB_RING_FILE`. Complex and node configuration files for EST are written to the `/spp/data` directory. A complex list is written to `/spp/data/config` for use by Convex Error Response System (CERS) software.

Once all information is in place, `ccmd` monitors the node for changes in status. `ccmd` waits for commands from other diagnostic utilities to set or clear certain system status variables. After a 60 second pause, `ccmd` once again broadcasts to determine which nodes are available. As each node responds, `ccmd` queries it for error conditions. Also, each node is checked to see if it has just powered up. If all nodes do not respond, then `ccmd` reports that no nodes are responding.

If no nodes are responding, `ccmd` clears all node data and waits for a node to respond. If a node powers up, the entire database is rebuilt.

If a node has stopped responding, `ccmd` clears just that node's data in the database.

If `ccmd` detects a hard error, it starts the `hard_logger` script to extract additional information from the node through the JTAG interface.

`ccmd` sends output to the console. If running under X-windows as `sppuser`, it sends its output to the test station console message output window. The `-d` debug option generates a substantial amount of console output.

`ccmd` does respond to several signals. The `sighup` signal tells `ccmd` to rebuild the test station database. A `sigint` or `sigabrt` signal terminates the `ccmd` process.

ccmu

`ccmu` is a text-based tool that can modify the reconfiguration parameters initialized by `POST`.

`ccmu` is started by the user from the test station either in command line or interactive mode. Once started, it attaches to the test station database created by `ccmd`. `ccmu` also reads the `/spp/data/complex.info` file to maintain a list of all possible nodes that could be reconfigured.

Note

Cross-check the test station database and the `complex.info` file with the `system -check` command.

`ccmu` command line parameters have the following format:

```
ccmu command [[: command]... [: command]]
```

Each command is the same format as those of the interactive `ccmu`.

In the interactive mode, `ccmu` is started by the command, `ccmu`, executed at a shell prompt. The following user prompt appears when `ccmu` is running interactively:

```
ccmu>
```

When a command is issued, `ccmu` communicates with the `system` through the JTAG interface to read or write the data and instructions required to accomplish the command.

Note

It is presumed that the user has some knowledge of how `POST` sets configuration parameters to enable or disable them.

Since `scan` is a slow operation, data retrieved from the node is kept on the test station. If the data is not present, it is retrieved. If it is present, the local copy is used.

Local data can be scanned back into the node by entering the `push` command. To acquire a fresh copy of node data, enter the `get -f` command to force a new copy of the data to be read.

In order to reconfigure a system, the user should use the `rebuild <node number> defaults` command. Table 3 lists `ccmu` command.

Table 3 `ccmu` commands

Command syntax	Command function
<code>quit</code>	Leave <code>ccmu</code> interactive mode.
<code>help</code>	Display the help screen.
<code>system [-check]</code>	Check the system configuration or display information on the complex.
<code>assign <node number> <ENRB number></code>	Reassigns the node with the backplane indicated to the new node number.
<code>assign <node number> <ENRB number> <complex serial number> <complex key></code>	Reassigns the complex serial number on the node indicated.
<code>list <node number> <parameter></code>	Displays a list of all POST parameters that match the parameter field. The parameter field may contain wild card characters.
<code>get [-f -s] <node number> <parameter></code>	Display the value for the parameter specified. If the data is already present on the test station and the <code>-f</code> option is not used the local copy is used.
<code>push <node number></code>	Sends the test station data to the node.
<code>put <node number> <parameter> <value></code>	Assigns value to the parameter on the local copy of the node data.
<code>mnetcache <node number> <net cache size number></code>	Assigns the network cache memory size to be the value specified.
<code>msize <node number> <? memory size number></code>	Deconfigures enough memory to be the memory size. If size is "?" all memory is reconfigured.
<code>stop_on_hard <node number> [<on> <off>] chk</code>	Sets an option bit in all ASICs that stops clocks as soon as an error is detected.
<code>query <node number> <A C M D number I S ></code>	Displays the current status of the system component specified. For a description of arguments, see text.
<code>toggle <node number> <A number C number M number D number_number_number I number S number></code>	Changes the local copy of the current status of the system component specified.
<code>nodemap <node number></code>	Change multi-node configuration map.
<code>rebuild <all node number> <default new></code>	Restart POST to enable a new or the default configuration.

In Table 3, the arguments in the Boot Map command are defined as follows:

- A or A number—Applies to all agents (EPACs) or individual agents 0-7.
 - Agent 0 is also known as p0l.
 - Agent 7 is also known as p7l.
- C or C number—Applies to all CPUs or individual CPUs 0 through 15.
 - CPU 0 is also known as pb0l.
 - CPU 1 is also known as pb0r.
- M or M number—Applies to all Memory boards mb0l through mb7l.
- D number or D number_number_number—Applies to the DIMM on memory board.
 D number_number_number is the <memory board>_<dimm>_<row>
- I or I number—Applies to all IO boards, such as iolf_a.
 - 0 is iolf_a
 - 1 is iolr_a
 - 2 is iorr_a
 - 3 is iorf_a
 - 4 is iolf_b
 - 5 is iolr_b
 - 6 is iorr_b
 - 7 is iorf_b
- SCI or SCI number—Applies to all IO boards, such as iolf_a
 0 refers mb0l_t; 7 refers to mb7l_t

The parameter names associated with POST configuration do not agree with the name physically on the hardware or hardware name. The name used by POST is called the logical name. Table 4 displays typical logical names and the hardware name.

Table 4 Logical and Hardware Names

Logical name	Hardware name
emb0 - emb7	mb0l, mb1l, mb2r, mb3r, mb4l, mb5,l mb6r,mb7r
epac0-epac7	p0l, p1r, p2l, p3r, p4l, p5r, p6l, p7r
cpu0-cpu15	pb0l, pb0r, pb1r, pb1l, pb2l, pb2r, pb3r, pb3l, pb4l, pb4r, pb5r, pb5l, pb6l, pb6r, pb7r, pb7l

Table 4 Logical and Hardware Names—(continued)

Logical name	Hardware name
emb0_etac-emb7_etac	mb0l_t, mb1l_t, mb2r_t, mb3r_t, mb4l_t, mb5l_t, mb6r_t, mb7r_t
epic0-epic7	iolf_b, iolr_b, iorr_b, iorf_b, iolf_a, iolr_a, iorr_a, iorf_a
emb0_epmb0_row0 - emb0_epmb15_row1	mb0l_B0S0_row0, mb0l_B0S0_row1, mb0l_B0S1_row0, mb0l_B0S1_row1, mb0l_B0S2_row0, mb0l_B0S2_row1, mb0l_B0S3_row0, mb0l_B0S3_row1, mb0l_B2S4_row0, mb0l_B2S4_row1, mb0l_B2S5_row0, mb0l_B2S5_row1, mb0l_B2S6_row0, mb0l_B2S6_row1, mb0l_B2S7_row0, mb0l_B2S7_row1, mb0l_B1S0_row0, mb0l_B1S0_row1, mb0l_B1S1_row0, mb0l_B1S1_row1, mb0l_B1S2_row0, mb0l_B1S2_row1, mb0l_B1S3_row0, mb0l_B1S3_row1, mb0l_B3S4_row0, mb0l_B3S4_row1, mb0l_B3S5_row0, mb0l_B3S5_row1, mb0l_B3S6_row0, mb0l_B3S6_row1, mb0l_B3S7_row0, mb0l_B3S7_row1,

xconfig

xconfig is the graphical tool that can also modify the parameters initialized by POST to reconfigure a node.

The graphical interface allows the user to see the configuration state. Also the names are consistent with the hardware names, since individual configuration parameters are hidden to the user. The drawback of xconfig is that it can not be used as a part of script-based tests, nor can it be used for remote debug.

xconfig is started from a shell as ccmu is. It reads the test station database and the possible nodes from /spp/data/complex.info.

Information on node 0 is read and interpreted to form the starting X-windows display shown in Figure 3.

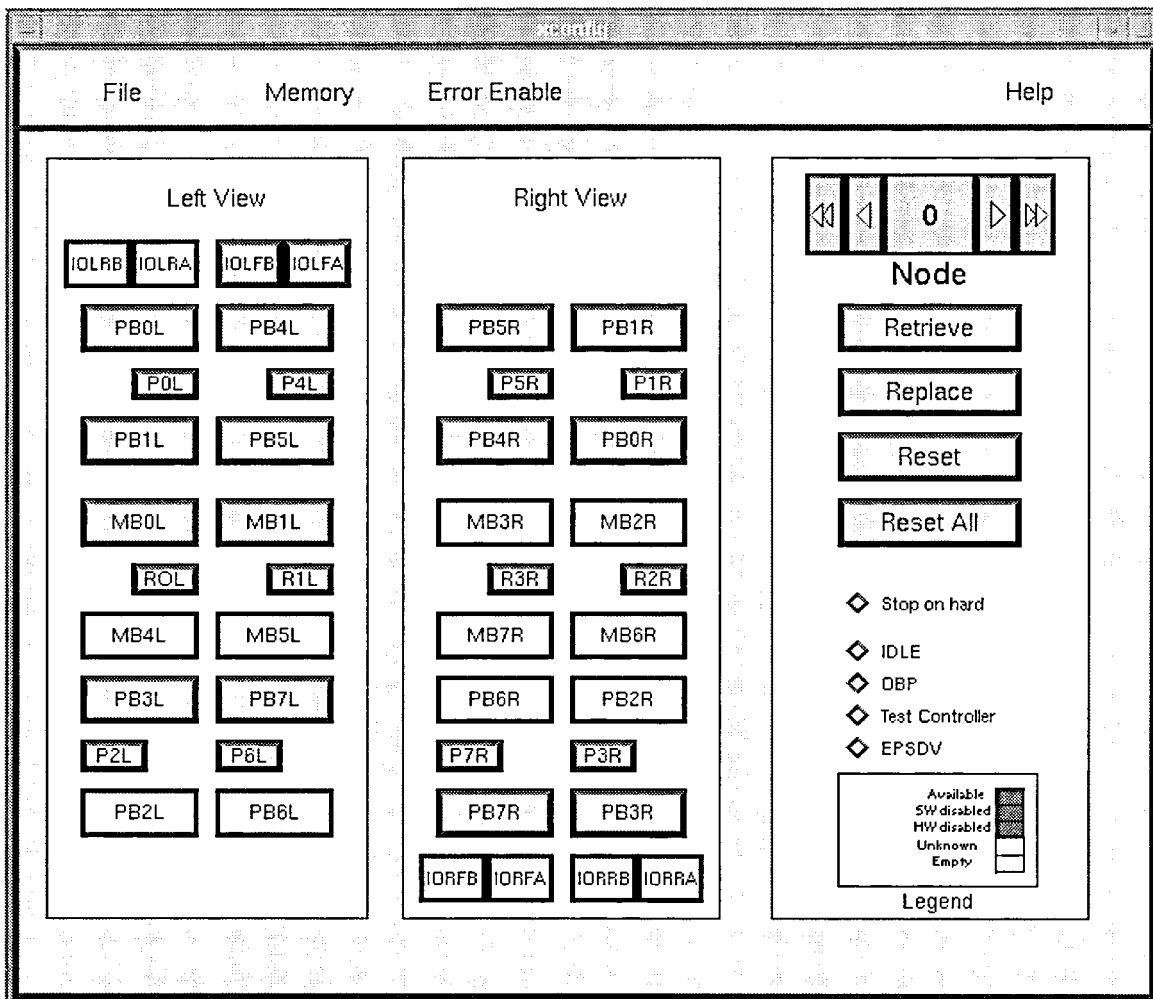


Figure 3 xconfig window

As buttons are clicked, the item selected changes state and color. There is a legend on the screen to explain the color and status. The change is recorded in the test stations image of the node.

When the user is satisfied with the new configuration, it should be replaced back into the node, and the node should be reset to enable the changes.

The main xconfig window has three sections:

- Menu bar—Provides additional capability and functions.
- Node configuration map—Provides the status of the node.

- Node control panel—Provides the capability to select a node and control the way data flows to it.

Menu bar

The menu bar appears at the top of the `xconfig` main window. It has four menus that provide additional features:

- File menu—Displays the file and exit options.
- Memory menu—Displays the main memory and CTI cache memory options.
- Error Enable menu—Displays the device menu options for error enabling and configuration.
- Help menu—Displays the help and about options.

The menu bar is shown in Figure 4.

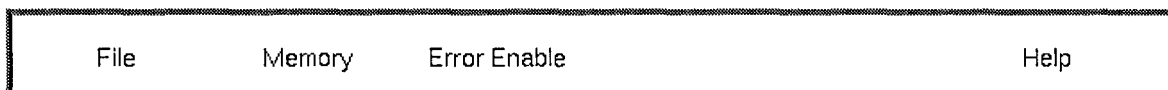


Figure 4 `xconfig` window menu bar

The File menu provides the capability to save and restore node images and to exit `xconfig`.

The Memory menu provides the capability to enable or disable memory at the memory DIMM level by the total memory size and to change the network cache size on a multinode complex.

The Error Enable menu provides the capability to change a device's response to an error condition. This is normally only used for troubleshooting.

The Help menu provides a help box that acts as on-line documentation and also contains program revision information.

Node configuration map

The node configuration map is a representation of the left and right side views of a node as shown in Figure 5.

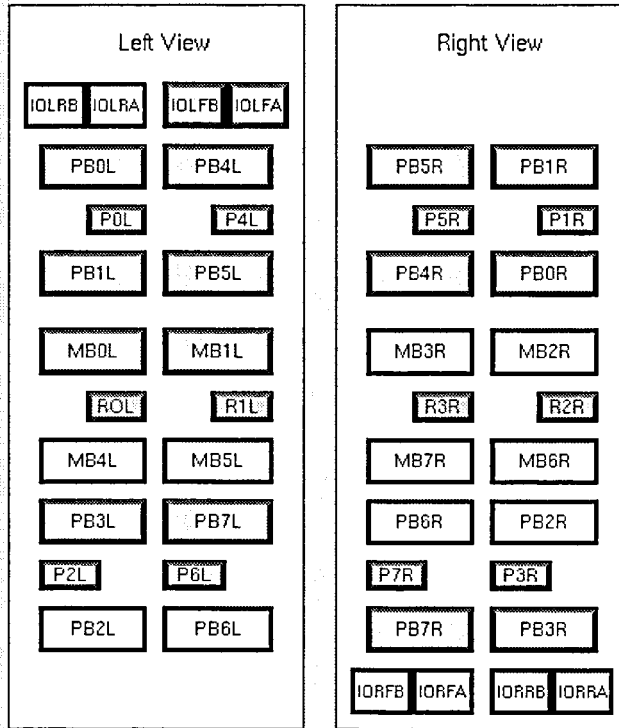


Figure 5 xconfig window node configuration map

The button boxes are positioned to represent the actual boards as viewed from the left and right sides. Each of the configurable components of the node is in the display.

A green button indicates that the component is present and enabled.

A red button indicates that the component is software disabled in the system.

A white button indicates that it is not possible to determine what the status of the component would be if POST were to be started.

A blue box indicates that the component is either not present or fails the power-on self tests.

A brown button indicates that POST had to hardware deconfigure this component in order to properly execute.

The colors are shown in the legend box of the node control panel. Components can change from enabled to disabled or disabled to unknown by clicking on the appropriate button with the left mouse button.

A multinode system requires an additional component on a memory board to enable the scalable coherent memory interface. This component can be viewed by right clicking the on the memory board button. The right mouse button toggles the memory board display between the memory board and the SCI device

Node control panel

The node control panel allows the user to select a node, select the stop clocks on an error function, select the boot parameters for a node and direct data flow between the node and the `xconfig` utility. It is shown in Figure 6.

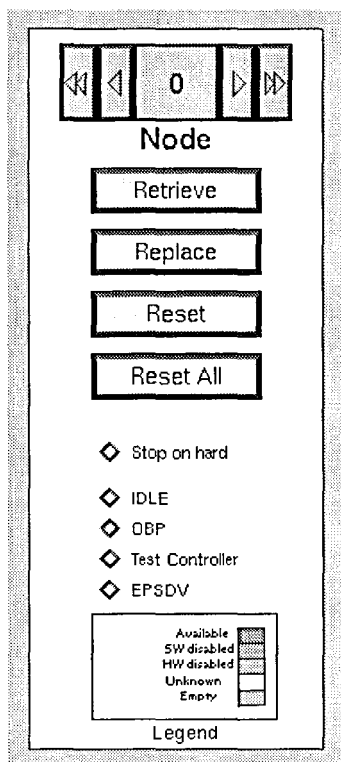


Figure 6 `xconfig` window node control panel

The node number is shown in the node box. A new number can be selected using the arrow buttons. The single arrow advances the

node counter by one. The double arrow advances the node counter by four.

When a new node is selected and available, its data is automatically read, and the node configuration map updated. The data image is kept on the test station until it is rebuilt on the node using the Replace button. This is similar to the push command on ccmu.

Even though data can be rebuilt on a node, it does not become active until POST runs again and reconfigures the system. The Reset or Reset All buttons can be used to restart POST on one or all nodes of a system. A multinode system requires a reset all to properly function.

A Retrieve button is available on the node control panel to get a fresh copy of the parameters settings in the system. Clicking this button overwrites the setting local to the test station and xconfig.

The Stop-on-hard button is typically used to assist in fault isolation. It stops all system clocks shortly after an error occurs. Only scan-based operations are available once system clocks have stopped.

The last group of buttons control what happens after POST completes. The node can become idle or boot OBP, the test controller or EPSDV. The test controller and EPSDV are additional diagnostic modes.

The PUC contains firmware in EEPROM known as Power-On Self Test (POST) routine. This chapter describes how POST initializes a node and handles power up errors.

Overview

Upon power up, all processors and hardware must be initialized before the node proceeds with booting. POST begins executing and brings up the node from an indeterminate state and then executes OBP.

None of the POST routines can be directly controlled via a user interface. Program control is provided by a set of configuration parameters (processing flags and variable definitions) stored in EEPROM by OBP, ccmu, or xconfig.

The error reporting modules display error codes for all fatal errors that occur during the POST execution. Any errors that can be recovered from, by reconfiguring the hardware, will be reported to OBP. POST status is reflected on the LCD display.

POST performs the following tasks:

- Initializes each processor in the node
- Validates all shared data structures within the EEPROM
- Initializes the core logic required to start OBP execution
- Determines node configuration
- Initializes all ASICs
- Initializes main memory
- Sets up CTI cache
- Invokes OBP

Any fatal errors are reported to the user via the system LCD. POST passes node configuration and any options to OBP via shared data structures.

Reset

POST may be invoked by one of the following types of reset:

- Powerup reset
- Hard reset
- Soft reset
- Transfer of control (TOC)

Power up reset

Power up reset occurs when power is applied to the node. The PUC deasserts reset which is synchronized with TCLK to provide a synchronous reset to all controllers. The processors build a node configuration and memory map. They also read the midplane COP chip to determine node ID. All MACs automatically begin refresh cycles.

Hard reset

Hard reset occurs when the Hard Reset bit in the PUC reset register is set. The PUC asserts the RESET line for approximately 100 msec and then releases it, producing a synchronous reset to the node.

Hard reset can also be invoked by scanning a value of one into the Hard Reset bit. The processors perform the same sequence as in a power up reset, including memory initialization and sizing. Hard reset by scanning allows complete initialization of a node remotely by the user.

Soft reset

Soft reset occurs when the Soft Reset bit in the PUC Reset register is set. The PUC asserts the RESET line for approximately 100 msec and then releases it, producing a synchronous reset to the node.

Soft reset can be invoked by scanning a value of one into the Soft Reset bit. Each processor initializes all CSRs in each controller but does not initialize or size memory, or initialize any part of the node that has been deconfigured.

TOC

The transfer of control reset occurs when one of the following conditions exist:

- The TOC button is pushed.
- The TOC bit in the PUC reset register is set.
- The TOC bit in the PUC CSR is set by scanning.

The `do_reset` routine also asserts TOC.

All processors in the node trap into the TOC vector in processor-dependent code (PDC) space.

POST modules

POST contains the following modules:

- Core Logic SRAM Initialization—Initializes all the SRAM space in the core logic to a known state. It also initializes parity for the SRAM.
- Configuration Determination and ASIC Hardware Initialization—Determines the ASIC population and sets the ASIC CSRs to a default state to prepare for main memory initialization. It initializes core logic utilities ASICs at the beginning of this process.
- Main Memory Initialization—Configures the memory interleave hardware and initializes all of main memory to valid data, ECC, and tag values for both local memory and CTI cache. The main memory population is reported to OBP.
- Error Reporting—Sets up and maintains the boot error log and boot status word in the EEPROM and reports errors to the LCD.

Node initialization

When power is applied to each node, all controllers in the node receive a power-up reset signal. POST provides a controlled node initialization and prepares it for booting OBP. Figure 7 shows of how POST initializes a node.

Processor initialization and selftest

Upon reset, all processors are initialized and placed in selftest. The extent of the selftest is determined by a mode bit in nonvolatile static random access memory (NVRAM).

Upon successful completion of processor selftest, the existence of each possible slice is determined. This is accomplished by reading the revision register of each PAC, PCI-bus Interface Controller (PIC), Memory Array Controller (MAC), and Toroidal Access Controller (TAC). Each processor will determine its processor ID from the PAC. Also, each processor fetches the Processor Semaphore register on the PUC. Because register requests are queued, one processor will fetch this CSR before the others and becomes the booting, or *monarch*, processor. All others go into a

command wait idle loop. The booting processor begins executing POST code from the PUC EEPROM.

Checksum verification of NVRAM

The PUC EEPROM contains the POST, OBP, and node diagnostics code. In addition, these three routines use shared data structures. The shared data structures reside in sections of the NVRAM. Each data structure has an embedded checksum word. POST checks the validity of each shared data structure by reading and comparing its checksum.

Core logic initialization

The core logic contains SRAM and DUARTs that support external terminal connection for self test and the LCD panel. POST initializes the SRAM, DUARTs, and all controller CSRs in the node.

node configuration determination

POST determines which and how many ASICs reside in the system (not every system contains a full complement of support hardware). It also determines the number of memory modules and their sizes. Any ASIC that does not respond to any CSR access is considered to be not installed.

node ASIC initialization

POST sets every node controller to a known state. The state is based both on configuration parameters and the current hardware configuration.

node main memory initialization

The processor reads the node ID from the COP and uses its information to load the Local node ID register.

Next, the monarch processor determines the memory configuration for all EMACs. It determines the size, population, and installation of each SIMM on a memory board and returns this information to the POST. The results are compared with the results of each other memory mapping and the least common

denominator is determined and mapped in. Once the memory population is determined, the memory and tags are initialized.

node clean up and OBP boot process

The POST resets the PUC Processor Semaphore CSR and cleans up any residual state information from the initialization process. All processors now begin to execute the OBP routine at approximately the same time.

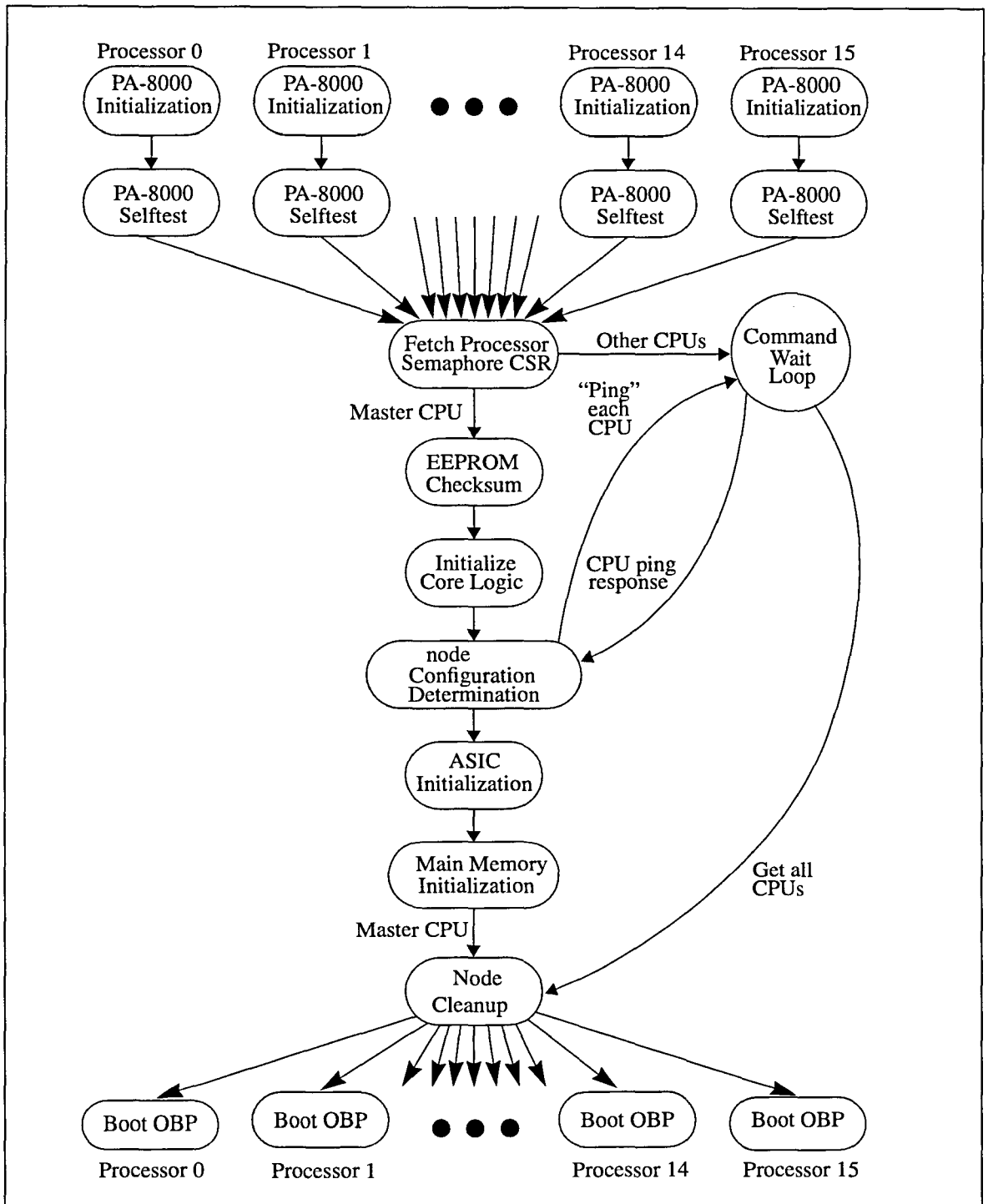


Figure 7 POST program flow

dcm script

The `dcm` script looks for PERL code in `/spp/bin/perl` and reads, parses, and prints to the screen the boot configuration map in NVRAM through calls to `sppdsh`. The script usage is:

```
dcm <Node number>
```

where `<Node number>` is a hex value and is the node on which to run `dcm` (in hex).

The following example runs `dcm` on nodes 0 and 4.:

```
% dcm 0 4
```

The following example displays the `dcm` help file:

```
% dcm -h
```

Running `dcm` provides the following information:

- Checksum for Boot configuration Map data structure
- Boot Configuration Map size
- POST Revision version used to create the Boot Configuration Map
- Processor cache (instruction cache, data cache) size in MB
- PACs (PASS, FAIL, or EMPTY)
- Status of PICs (PASS, FAIL, or EMPTY)
- Status of MACs (PASS, FAIL, or EMPTY)
- Status of TACs (PASS, FAIL, or EMPTY)
- Location of memory boards

Figure 8, Figure 9, and Figure 10 together show a single output example of entering the following on the command line:

```
% dcm 0
```

Excalibur Configuration Map Dump: Node: 0

=====

VERSION: 001.000.000.000 compiled: 1996/10/10 13:23:07 by: mullins

Acquiring the Boot Configuration Map...

 Check Sum: 0xf1a83645

 Boot Config Map Size: 113 Words

 POST Revision: 1.7.0.0

CPUs (ICache, DCache) Size in Bytes

=====

PB0L - PASS (1048576, 1048576) PB0R - PASS (1048576, 1048576)

PB1L - PASS (1048576, 1048576) PB1R - PASS (1048576, 1048576)

PB2L - PASS (1048576, 1048576) PB2R - PASS (1048576, 1048576)

PB3L - PASS (1048576, 1048576) PB3R - PASS (1048576, 1048576)

PB4L - PASS (1048576, 1048576) PB4R - PASS (1048576, 1048576)

PB5L - PASS (1048576, 1048576) PB5R - PASS (1048576, 1048576)

PB6L - PASS (1048576, 1048576) PB6R - PASS (1048576, 1048576)

PB7L - PASS (1048576, 1048576) PB7R - PASS (1048576, 1048576)

EPACs

=====

P0L - PASS P4L - PASS

P1R - PASS P5R - PASS

P2L - PASS P6L - PASS

P3R - PASS P7R - PASS

EPICs

=====

IOLF_B - PASS IOLF_A - PASS

IOLR_B - EMPTY IOLR_A - EMPTY

IORR_B - EMPTY IORR_A - EMPTY

IORF_B - EMPTY IORF_A - EMPTY

EMACs

=====

MB0L_M - PASS MB4L_M - PASS

MB1L_M - PASS MB5L_M - PASS

MB2R_M - PASS MB6R_M - PASS

MB3R_M - PASS MB7R_M - PASS

ETACs

=====

MB0L_T - EMPTY MB4L_T - EMPTY

MB1L_T - EMPTY MB5L_T - EMPTY

MB2R_T - EMPTY MB6R_T - EMPTY

MB3R_T - EMPTY MB7R_T - EMPTY

Figure 8 dcm sample output part A

Memory: B(ank#)S(lot#) - Row_0/Row_1

=====

EMB0:

=====

B0S0 - 16MB/16MB	B0S1 - 16MB/16MB	B0S2 - 16MB/16MB	B0S3 - 16MB/16MB
B1S0 - 16MB/16MB	B1S1 - 16MB/16MB	B1S2 - 16MB/16MB	B1S3 - 16MB/16MB
B2S4 - 16MB/16MB	B2S5 - 16MB/16MB	B2S6 - 16MB/16MB	B2S7 - 16MB/16MB
B3S4 - 16MB/16MB	B3S5 - 16MB/16MB	B3S6 - 16MB/16MB	B3S7 - 16MB/16MB

EMB1:

=====

B0S0 - 16MB/16MB	B0S1 - 16MB/16MB	B0S2 - 16MB/16MB	B0S3 - 16MB/16MB
B1S0 - 16MB/16MB	B1S1 - 16MB/16MB	B1S2 - 16MB/16MB	B1S3 - 16MB/16MB
B2S4 - 16MB/16MB	B2S5 - 16MB/16MB	B2S6 - 16MB/16MB	B2S7 - 16MB/16MB
B3S4 - 16MB/16MB	B3S5 - 16MB/16MB	B3S6 - 16MB/16MB	B3S7 - 16MB/16MB

EMB2:

=====

B0S0 - 16MB/16MB	B0S1 - 16MB/16MB	B0S2 - 16MB/16MB	B0S3 - 16MB/16MB
B1S0 - 16MB/16MB	B1S1 - 16MB/16MB	B1S2 - 16MB/16MB	B1S3 - 16MB/16MB
B2S4 - 16MB/16MB	B2S5 - 16MB/16MB	B2S6 - 16MB/16MB	B2S7 - 16MB/16MB
B3S4 - 16MB/16MB	B3S5 - 16MB/16MB	B3S6 - 16MB/16MB	B3S7 - 16MB/16MB

EMB3:

=====

B0S0 - 16MB/16MB	B0S1 - 16MB/16MB	B0S2 - 16MB/16MB	B0S3 - 16MB/16MB
B1S0 - 16MB/16MB	B1S1 - 16MB/16MB	B1S2 - 16MB/16MB	B1S3 - 16MB/16MB
B2S4 - 16MB/16MB	B2S5 - 16MB/16MB	B2S6 - 16MB/16MB	B2S7 - 16MB/16MB
B3S4 - 16MB/16MB	B3S5 - 16MB/16MB	B3S6 - 16MB/16MB	B3S7 - 16MB/16MB

EMB4:

=====

B0S0 - 16MB/16MB	B0S1 - 16MB/16MB	B0S2 - 16MB/16MB	B0S3 - 16MB/16MB
B1S0 - 16MB/16MB	B1S1 - 16MB/16MB	B1S2 - 16MB/16MB	B1S3 - 16MB/16MB
B2S4 - 16MB/16MB	B2S5 - 16MB/16MB	B2S6 - 16MB/16MB	B2S7 - 16MB/16MB
B3S4 - 16MB/16MB	B3S5 - 16MB/16MB	B3S6 - 16MB/16MB	B3S7 - 16MB/16MB

EMB5:

=====

B0S0 - 16MB/16MB	B0S1 - 16MB/16MB	B0S2 - 16MB/16MB	B0S3 - 16MB/16MB
B1S0 - 16MB/16MB	B1S1 - 16MB/16MB	B1S2 - 16MB/16MB	B1S3 - 16MB/16MB
B2S4 - 16MB/16MB	B2S5 - 16MB/16MB	B2S6 - 16MB/16MB	B2S7 - 16MB/16MB
B3S4 - 16MB/16MB	B3S5 - 16MB/16MB	B3S6 - 16MB/16MB	B3S7 - 16MB/16MB

Figure 9 dcm sample output part B

EMB6:

=====

B0S0 - 16MB/16MB	B0S1 - 16MB/16MB	B0S2 - 16MB/16MB	B0S3 - 16MB/16MB
B1S0 - 16MB/16MB	B1S1 - 16MB/16MB	B1S2 - 16MB/16MB	B1S3 - 16MB/16MB
B2S4 - 16MB/16MB	B2S5 - 16MB/16MB	B2S6 - 16MB/16MB	B2S7 - 16MB/16MB
B3S4 - 16MB/16MB	B3S5 - 16MB/16MB	B3S6 - 16MB/16MB	B3S7 - 16MB/16MB

EMB7:

=====

B0S0 - 16MB/16MB	B0S1 - 16MB/16MB	B0S2 - 16MB/16MB	B0S3 - 16MB/16MB
B1S0 - 16MB/16MB	B1S1 - 16MB/16MB	B1S2 - 16MB/16MB	B1S3 - 16MB/16MB
B2S4 - 16MB/16MB	B2S5 - 16MB/16MB	B2S6 - 16MB/16MB	B2S7 - 16MB/16MB
B3S4 - 16MB/16MB	B3S5 - 16MB/16MB	B3S6 - 16MB/16MB	B3S7 - 16MB/16MB

Figure 10 dcm sample output part C

The test controller is an EEPROM-based utility that provides the environment for executing the offline diagnostic tests. It is controlled through parameters stored in the NVRAM on the Utilities board. The test controller reads these parameters to determine its execution mode, the number processors to test, which MACs to include in the testing, which subtests to run, and other diagnostic test specific information.

Test controller modes

There are two basic operational modes for this utility:

- Stand-alone mode
- Interactive mode

In stand-alone mode, `cxtest` invokes the test controller. The test controller reads test parameters from NVRAM (these parameters are written into NVRAM by `cxtest` before it invokes the test controller), executes the test and subtests specified in NVRAM, and sets a completion bit in NVRAM when the test and subtests are finished. `cxtest` is described in Chapter 5.

In interactive mode, a user interface allows the user to select the processors to test, select the subtests to run, and examine error information. The user interface is a set of menus described in this chapter.

In the interactive mode, the test controller loops waiting for the `start` command. Prior to issuing the `start` command, any global and/or processor specific parameters can be modified. Other tests can be loaded into main memory. By modifying a few processor test parameters, the test controller interfaces with these tests. When all tests have completed, the test controller waits for the next `start` command. Any combination of parameter and tests may be modified and executed.

User interface

There is a common interface for subtests to access the test parameters and report events to the test controller. The test controller provides for the control of offline diagnostic test execution. It utilizes a set of parameters to control its operation. The parameters consist of the following:

- Global set that controls the overall operation of the test controller
- Test set (one per test) that controls how the tests are executed by the test controller
- CPU parameters (one per processor) that contain status information about the tests executing on each processor

All these parameters are in NVRAM.

The user interface allows the user to modify parameters that reside in NVRAM, thereby controlling the operation of the test controller. It also allows the user to select which subtests are executed on each of the processors and modify the test parameters, as well as any other test information.

The test controller user interface consists of two basic menus. The first is the main menu that gives the user the following capabilities:

- Modify the POST boot selection
- Control operation of the test controller
- Display the current global parameter selections
- Display processor summary
- Switch processors
- Go to the Test Configuration menu

The second menu is the processor Test Control menu that provides the following capabilities:

- Select classes of subtests to execute
- Select subtests to execute
- Specify pause enables
- Specify whether to loop or not
- Specify the test and/or subtest error counts
- Read and write the 20 words of test specific information
- Select the hardware to test
- Display the current parameter selections

Main menu

Figure 11 shows the test controller main menu.

```
MAIN Menu commands

0=Quit Test Controller
1=Begin Test Controller Execution
2=Halt Test Controller Execution
3=Resume Test Controller Execution
4=Switch CPU
5=POST Boot Selection
6=Execution Mode Selection
7=Global Parameter Display
8=CPU Summary Display
9=Display CPU Errors
A=Test Selection Menu
B=Test Configuration Menu
C=Debugging Menu
D=Display revision

Enter Command:
```

Figure 11 Main menu

Each main menu selection is defined as follows:

- 0=Quit Test Controller—Terminates the test controller utility and either reboots the system (to POST and then to the selected program) or halts the system depending on the current value of the POST Boot Selection flag.
- 1=Begin Test Controller Execution—Starts the test controller utility executing the specified subtests on the selected processors. The entire system is started from the beginning.
- 2=Halt Test Controller Execution—Suspends temporarily the operation of the test controller. This command may be entered at any time. Only the test controller is halted; subtests on other processors continue to execute.
- 3=Resume Test Controller Execution—Continues execution from the point of interruption.
- 4=Switch CPU—Allows the user to start the test controller on the specified processor. The previously used processor starts executing the command wait loop code. The user is prompted for the processor as follows:

```
Enter CPU (0-f):
```

- 5=POST Boot Selection—Prompts the user for the new value with the following prompt:

POST Boot Selection (0=Spin, 1=OBP, 2=Diags, 3=Standalone Diags, 4=Dumper 5=EPSDV):

The user must enter in value between 0 and 4 inclusive. Each of these values is further defined in Table 5.

Table 5 POST Boot Selections

Selection	Description
0	POST enters it's spin wait loop.
1	POST boots to OBP.
2	POST boots to the test controller (interactive mode).
3	POST boots to the test controller (standalone mode).
4	POST boots to RDR dumper.
5	POST boots to EPSDV.

For all values, POST boots to EPSDV, the test controller performs a hard reset to POST when the test controller terminates.

- 6=Execution Mode Selection—Allows the user to select the mode for executing the subtests. The two options are serial and parallel. The following prompt queries for the selection:

Execution Mode Selection (0=serial, 1=parallel):

- 7=Global Parameter Display—Displays the available hardware components, the current "POST Boot Selection" value, and the current "Execution Mode Selection" value. The display is shown in Figure 12. The asterisks denote the component has passed POST processing and is available for

diagnostic testing (see CPUs 0-3 and EMACs 0, 2, 4, and 6 in the display).

MAIN Menu - Global Parameters Display

```
CPUs:           0* 1* 2* 3* 4  5  6  7  8  9  A  B  C  D  E  F
EPACs:          0* 1* 2  3  4  5  6* 7
EMACs:          0* 1  2* 3  4* 5  6* 7
ETACs:          0  1  2  3  4  5  6  7
EPICs:          0  1  2  3  4  5  6  7
POST Boot Selection:  Spin  OBP*  TC  Standalone  Dumper  EDPSDV
Execution Mode Selection: Serial  Parallel*
```

Figure 12 Main menu - Global Parameters display

- 8=CPU Summary display—Displays a summary of the current processor and testing information. An example of the display is shown in Figure 13. Each available hardware component is marked with an asterisk just to the right of its number (see CPUs 0-3 and EMACs 0, 2, 4, and 6 in the display).

MAIN Menu - CPU Summary Display

Total Failures = 00000000

Configuration Map

=====

```

CPUs:      0* 1* 2* 3* 4  5  6  7  8  9  A  B  C  D  E  F
EPACs:     0  1  2  3  4  5  6  7
ERACs:     0  1  2  3
EMACs:     0* 1  2* 3  4* 5  6* 7
ETACs:     0  1  2  3  4  5  6  7
EPICs:     0  1  2  3  4  5  6  7
    
```

CPU	STATE	FAIL COUNT	SUBTEST	TEST NAME
===	=====	=====	=====	=====
0	Idle	0	n/a	n/a
1	Idle	0	n/a	n/a
2	Idle	0	n/a	n/a
3	Idle	0	n/a	n/a
4	Idle	0	n/a	n/a
5	Idle	0	n/a	n/a
6	Idle	0	n/a	n/a
7	Idle	0	n/a	n/a
8	Idle	0	n/a	n/a
9	Idle	0	n/a	n/a
A	Idle	0	n/a	n/a
B	Idle	0	n/a	n/a
C	Idle	0	n/a	n/a
D	Idle	0	n/a	n/a
E	Idle	0	n/a	n/a
F	Idle	0	n/a	n/a

Figure 13 Main menu - Processor Summary display

The possible states in Figure 13 are described in Table 6.

Table 6 Processor States

CPU State	Description
Not Available	Denotes processor is not available for testing.
Running	Denotes a test is currently running on this processor.
Idle	Denotes that no test is running on this processor
Ready	Denotes last subtest completed and ready for next subtest
Test Completed	Denotes test completed execution on this processor.

Table 6 Processor States—(continued)

CPU State	Description
Error Detected	Denotes test halted due to an error condition on this processor.
Test Timeout	Denotes a timeout detected during test execution on this processor; the test is halted.
HW Reqs Not Met	Denotes the hardware selected does not meet the minimum hardware requires for executing the test.
User Halted	Denotes user halted test.
Unexpected HPMC	Denotes running test caused an HPMC; the test is halted.
SW Deconfigured	Denotes test automatically halted testing on this processor, because of a software restriction.

- 9=Display CPU Errors—Displays the errors for the currently selected processor. When selected, the user is prompted for the processor as follows:

Enter CPU [0-f]:

Figure 14 shows an example of this display. There are four fields:

- Date/Time—Date and time the error was logged.
- Subtest—Failing subtest number
- Event Code—32-bit event code
- Error Message—40-character error message

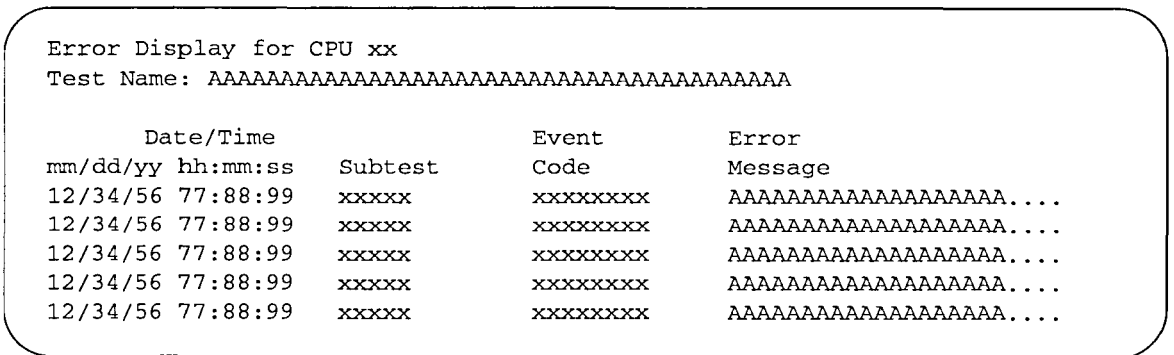


Figure 14 Test Configuration menu - Display processor Errors

- A=Test Selection Menu—Invokes the menu shown in Figure 15. This menu allows the user to select which tests to execute. An asterisk before the test name denotes that it has been selected. In Figure 15, only the memory test is selected. Selecting options 1 through A toggles the current state for that

particular test. Selecting option 0 returns the user to the main menu shown above in Figure 11.

```
MAIN Menu - Test Selection Display

0=Return to Main Menu
1=*Memory test
2=Architecture Features test
3=Intra-Node Coherency test
4=Inter-Node Coherency test
5=I/O test
6=CPU selftests
7=not available
8=not available
9=not available
A=not available

Please enter number of test:
```

Figure 15 Main menu - Test Selection menu

- **B=Test Configuration Menu**—Switches the user to the Configuration menu shown in Figure 17 for the specified test.
- **C=Debugging Menu**—Invokes the Debugging Menu shown in Figure 16 which allows the user to read or write to any memory location on the hypernode and dump various data.

```
MAIN Menu - Debugging Menu

0=Return to Main Menu
1=Read 32-bit Memory Location
2=Write 32-bit Memory Location
3=Read 64-bit Memory Location
4=Write 64-bit Memory Location
5=Dump DUART Port 0 Registers
6=Dump DUART Port 1 Registers
7=Dump SONIC Registers
8=Dump TC CPU Info Structure
9=Dump TC Test Info Structure
A=Dump PCXU General Registers
B=Dump PCXU Control Registers
C=Read ECC From Memory Line
D=Read Tag From Memory Line
E=Print Test Revision

Enter number of activity:
```

Figure 16 Main menu - Debugging menu

- Selection 1 queries for the 40-bit address to read as follows:
Enter 40-bit address:
- Selection 2 queries for the 40-bit address and then for the 32-bits of data to write:
Enter 32-bit data:
- Selection 3 queries for the 40-bit address to read.
- Selection 4 queries for the 40-bit address to write, and then for the 64-bits of data to write as follows:
Enter Upper 32-bits:
Enter Lower 32-bits:
- Selection 8 queries the user for the processor index as follows:
Enter cpu index [0-f]:
- Selection 9 queries the user for the test index with the prompt shown. The test indices for the various tests are shown above in Figure 15.
Enter test index [1-A]:
- Selections C and D query for the 40-bit address for which to display the ECC or tag of that memory line.
- Selection E queries the user for the test index with the following prompt:
Enter test index [1-A]:

Test Configuration menu

The Test Configuration menu is shown in Figure 17.

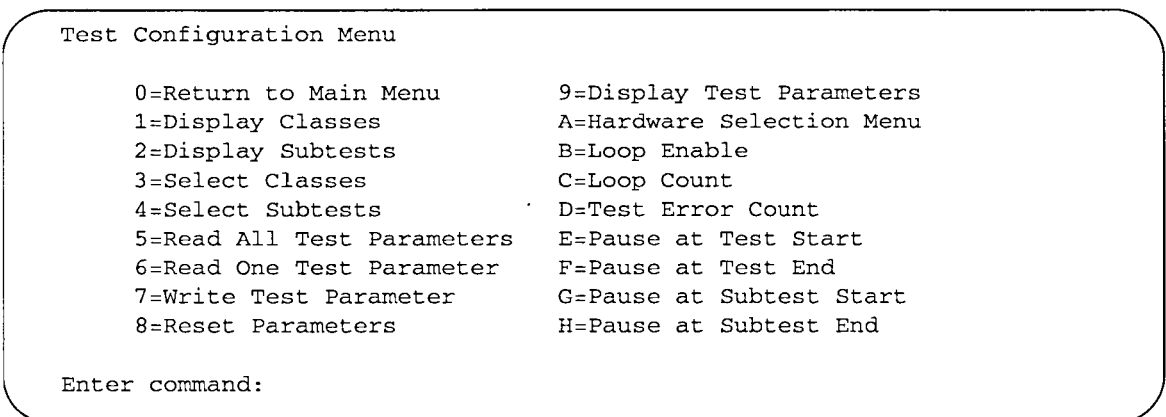


Figure 17 Test Configuration menu

Each Test Configuration menu selection is defined as follows:

- 0=Return to Main Menu—Returns the user to the Main menu shown in Figure 16.
- 1=Display Classes—Displays the current class definitions for this diagnostic. An example of the display is shown in Figure 18.

Test Configuration Menu - Class Display	
Class	Description
0	class 0 description
1	class 1 description
.	.
.	.
n	class n description

Figure 18 Test Configuration menu - Class display

- 2=Display Subtests—Displays the current subtest definitions for this diagnostic. An example of the display is shown in Figure 19.

Test Configurationl Menu - Subtest Display	
Subtest	Description
0	subtest 0 description
1	subtest 1 description
.	.
.	.
n*	subtest n description

Figure 19 Test Configuration menu - Subtest display

An asterisk following the subtest number denotes that it is selected for execution. For example, see the “n subtest n description” line.

- 3=Select Classes—Allows the user to specify which classes of subtests to execute. These selections are in addition to any subtests selected. The following prompt is displayed:

Enter class number:

The user must enter one of the following:

- An optional operator followed by a class number, for example 2, +2 or -2
- Multiple class numbers (class, +class, -class are allowed) separated by commas, for example 1,2,3

The class numbers are decimal.

- 4=Select Subtests—Allows the user to specify which subtests to execute. These selections are in addition to any classes selected. The following prompt is displayed:

Enter subtest number or subtest range:

The user may enter one of the following:

- A single subtest number
- A subtest range which consists of two numbers separated with a dash and is inclusive. An example of a valid range entry is 100-200.
- An optional operator followed by a subtest selection, for example 2, +2, -2, +100-200, or -100-200.

The subtest numbers are decimal values only.

- 5=Read All Test Parameters—Reads all 20 words that make up the test parameter set and displays this information. These test parameters reside in NVRAM and are defined by the particular test executing on this processor. An example of the display is shown in Figure 20.

Test Configuration Menu - Test Parameters			
Word	Value	Word	Value
0	0xhhhhhhhh	10	0xhhhhhhhh
1	0xhhhhhhhh	11	0xhhhhhhhh
2	0xhhhhhhhh	12	0xhhhhhhhh
3	0xhhhhhhhh	13	0xhhhhhhhh
4	0xhhhhhhhh	14	0xhhhhhhhh
5	0xhhhhhhhh	15	0xhhhhhhhh
6	0xhhhhhhhh	16	0xhhhhhhhh
7	0xhhhhhhhh	17	0xhhhhhhhh
8	0xhhhhhhhh	18	0xhhhhhhhh
9	0xhhhhhhhh	19	0xhhhhhhhh

Figure 20 Test Configuration menu - Test Parameters

- 6=Read One Test Parameter—Allows the user to read a single test parameter.
- 7=Write Test Parameter—Allows the user to modify any one of the test parameter words. The user is first requested to specify which word is to be modified:

Specify Test Parameter word [0-19]:

After specifying the word, the user is then prompted for the new value:

New value for Test Parameter word xx:

- 8=Reset Parameters—Resets some of the parameters to their default values. Table 7 lists the affected parameters and their default values.

Table 7 Parameter Defaults

Parameter	Default value
Loop Enable	0
Loop Count	0
Test Error Count	1
Pause At Test Start	0
Pause At Test End	0
Pause At Subtest Start	0
Pause At Subtest End	0

- 9=Display Test Parameters—Displays the current values of the processor parameters. An example of the display is shown in Figure 21. An asterisk denotes the current selections. For Example, processor 0 is selected.

This minimum hardware requirements information is enclosed in parentheses after the hardware type label and denotes the number of that type required. In the example below, 1 processor, 1 PAC (the one associated with the selected processor), and 1 MAC are needed.

The test controller compares the selected hardware components versus these minimum requirements to

determine if the test can be executed. Unless these minimum requirements are met, the test cannot be executed.

Test Configuration Menu - Test Parameters Display

```
CPUs: (1) 0* 1 2 3 4 5 6 7 8 9 A B C D E F
EPACs: (1) 0* 1 2 3 4 5 6 7
ERACs: (4) 0* 1* 2* 3*
EMACs: (1) 0* 1 2 3 4 5 6* 7
ETACs: (0) 0 1 2 3 4 5 6 7
EPICs: (0) 0 1 2 3 4 5 6 7
Nodes: (1)

Loop Enable:      ON      OFF*
Test Error Count: 10
Pause Test Start: ON      OFF*
Pause Test End:   ON      OFF*
Pause Subtest Start: ON    OFF*
Pause Subtest End: ON     OFF*
```

Figure 21 Test Configuration menu - Test Parameters display

- A=Hardware Selection menu—Invokes Hardware Selection menu shown in Figure 22.

Test Configuration Menu - Hardware Selection Display

```
0=Return to Test Configuration Menu
1=CPU Selection
2=EPAC Selection
3=EMAC Selection
4=ETAC Selection
5=EPIC Selection
6=Node Selection
Enter Command:
```

Figure 22 Test Configuration menu - Hardware Selection menu

The selection of the Hardware Selection menu are defined as follows:

- 1-5=<hardware> Selection—Selects the appropriate controller. The following prompt is displayed:

Select <hardware>:

The user must enter one of the following:

- * An optional operator followed by a hardware component number, for example 2, +2 or -2

- * Multiple hardware component numbers separated by commas, for example 1,+2,-3

The format 2, or +2, denotes to use this hardware component in testing. The format -2 denotes not to use this hardware component in testing. The 1 and +1 formats are equivalent, and leaving a hardware component out of the list is equivalent to the -n format.

As an example, to select all the even processors the user would enter:

0,2,4,6,8,a,c,e

- 6=Node Selection—Allows the user to enter 7-bit node ids. The format is similar to that used for processors, i.e. an optional operator can be used and multiple entries are allowed. The following prompt is used:

Enter Node Ids:

- B=Loop Enable—Allows the user to modify the value of the loop enable flag, which causes the test controller utility to loop on all selected subtests when the last subtest is executed. The user is prompted for the new value as follows:

Loop Enable (0=disabled, 1=enabled):

- C=Loop Count—Allows the user to specify the number of times to loop through the selected subtests. It is only used if the "Loop Enable" flag is set. The user is prompted for the new value (a decimal number) as follows:

Loop Count:

- D=Test Error Count—Allows the user to modify the maximum number of test errors that can occur before the test controller utility terminates execution of subtests on this processor. The user is prompted for the new value (a decimal number) as follows:

Test Error Count value (1-127, N=no limit):

A value of N means that there is no limit to the number of errors that can occur.

- E=Pause at Test Start—Allows the user to modify the pause at test start flag. This flag results in the test controller pausing the testing on this processor just prior to starting the process of determining the first subtest to execute. The user is prompted for the new value as follows:

Pause at Test Start (0=disabled, 1=enabled):

- Selection F - Pause at Test End—Allows the user to modify the pause at test end flag. This flag results in the test controller pausing the testing on this processor after last subtest has

completed execution and all cleanup is complete. The user is prompted for the new value as follows:

Pause at Test End (0=disabled, 1=enabled):

- G=Pause at Subtest Start—Allows the user to modify the pause at subtest start flag. This flag results in the Test Controller pausing the testing on this processor just prior to starting the execution of the current subtest. The user is prompted for the new value as follows:

Pause at Subtest Start (0=disabled, 1=enabled):

- H=Pause at Subtest End—Allows the user to modify the pause at subtest end flag. This flag results in the test controller pausing the testing on this processor just after detecting the current subtest has completed execution. The user is prompted for the new value as follows:

Pause at Subtest End (0=disabled, 1=enabled):

The `ctest` program is a graphical front end and a command line interpreter for the test controller. It is a standalone program that runs independently of any diagnostic tests loaded in the EEPROM on the Utilities board.

Overview

The `ctest` program runs on the test station and communicates with the test controller via the NVRAM configuration parameters on the Utilities board. Depending on the command line, `ctest` either starts the graphics display or runs as a command line interpreter.

The test controller must be in the standalone mode in order for `ctest` to be able to communicate with it. To run the test controller in standalone mode, run the `tc_standalone` script.

When `ctest` is invoked, it first retrieves system information from NVRAM and EEPROM on the Utilities board. This information includes:

- Tests loaded
- Parameters required for those tests
- Hardware configuration

The `ctest` program works with the test controller to execute tests based on the options selected by the user. It performs the following functions:

- Looping
- Dispatching tests
- Configuring hardware
- Retrieving error information from the test controller

The test controller operates in the standalone mode when running in conjunction with `ctest`. This is true whether one is using the command line version of `ctest` or the graphics interface.

Graphics interface

To start the `ctest` graphics interface, specify the `-d` option on the command line as follows:

```
% ctest -d
```

This causes `ctest` to open a window on the display. Where the window is displayed is set by the environment variable `$DISPLAY`. This cannot be changed on the command line.

The window has two areas of importance:

- Menu selections
- Test information display

Menus

There are six main menus in `ctest`. Figure 23 shows the `ctest` menu bar.

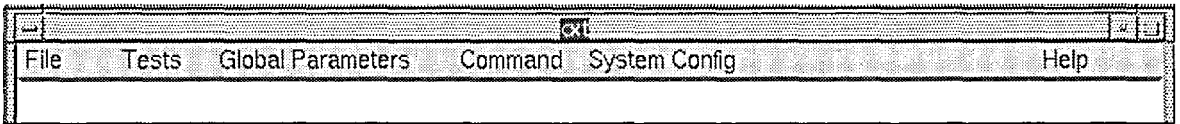


Figure 23 `ctest` menu

File menu

The File menu has the following options:

- Save Selections
- Restore Selections
- Log to File/Close Log File
- Clear Log
- Exit

The Save Selections and Restore Selections options save and restore specific tests or configurations, respectively. With the Restore Selections option, the user can run specific tests without having to go through all the button pushing.

The Log to File option saves the information that appears in the display area to a file. When invoked, the option changes to Close Log File. Selecting this option terminates the save operation, and the menu option reverts to Log to File.

The Clear Log option clears the display area on the screen but does not truncate the log file if the Log to File option is enabled.

The Exit option closes `ctest`.

When exiting `ctest`, the state of the Boot option is set to what is displayed in the System Configuration menu. The default is to return to OBP, so if the user intends to return to `ctest`, make sure the test controller standalone option is checked. See Figure 25.

Global Test Parameters menu

The Global Test Parameters menu contains the following controls for setting parameters that are not test specific:

- Looping
- Parallel execution of tests
- Pausing
- Continue on error controls

Clicking this menu option opens the window shown in Figure 24.

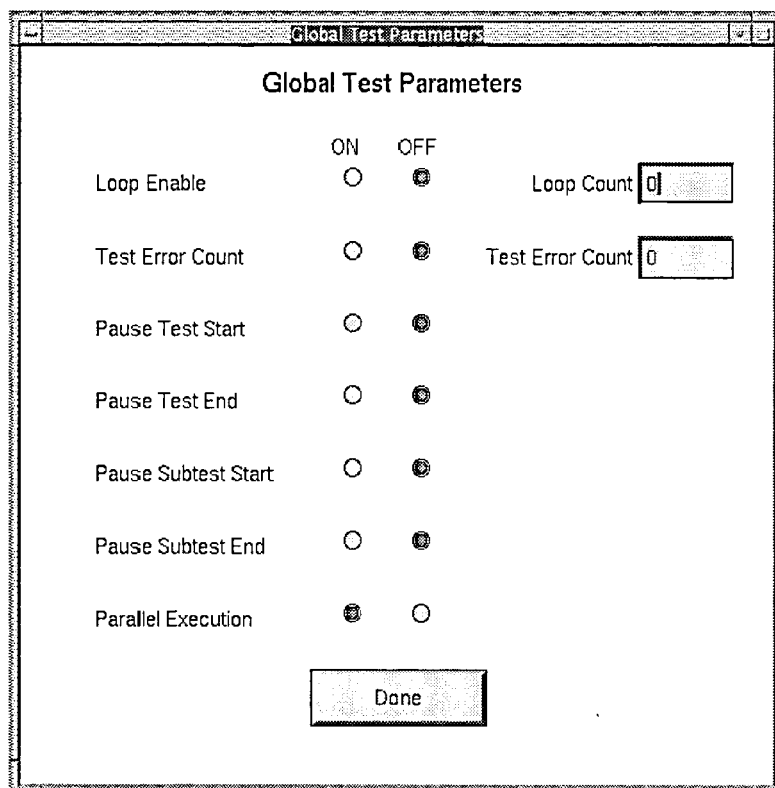


Figure 24 `ctest` Global Test Parameters menu

Command menu

The Command menu is used to perform actions on the node or complex being tested. These actions include:

- Go
- Reset Machine
- Read Boot Config Map

The Go option starts the selected tests.

The Reset Machine option resets the system.

The Reading the Boot Config Map option is necessary if the physical location of the boards being tested changes. It lets the user keep `cxtest` running while the node is powered off and boards are moved to a different location.

System Configuration menu

The System Configuration menu displays all nodes that were online at the time `cxtest` started. Clicking one of the menu entries opens a node configuration window (Node x Configuration window) that allows the user to select the hardware to test, excluding I/O-specific devices such as disk drives or PCI adapters. See Figure 25.

Any hardware selections made on this screen apply to all tests to be run. For example, to run test A with hardware configuration A and then test B with hardware configuration B, the configuration must be changed manually after test A is completed. The information contained in the hypernode configuration window is extracted from the boot configuration map. If this map changes, it can be reread using the Command menu.

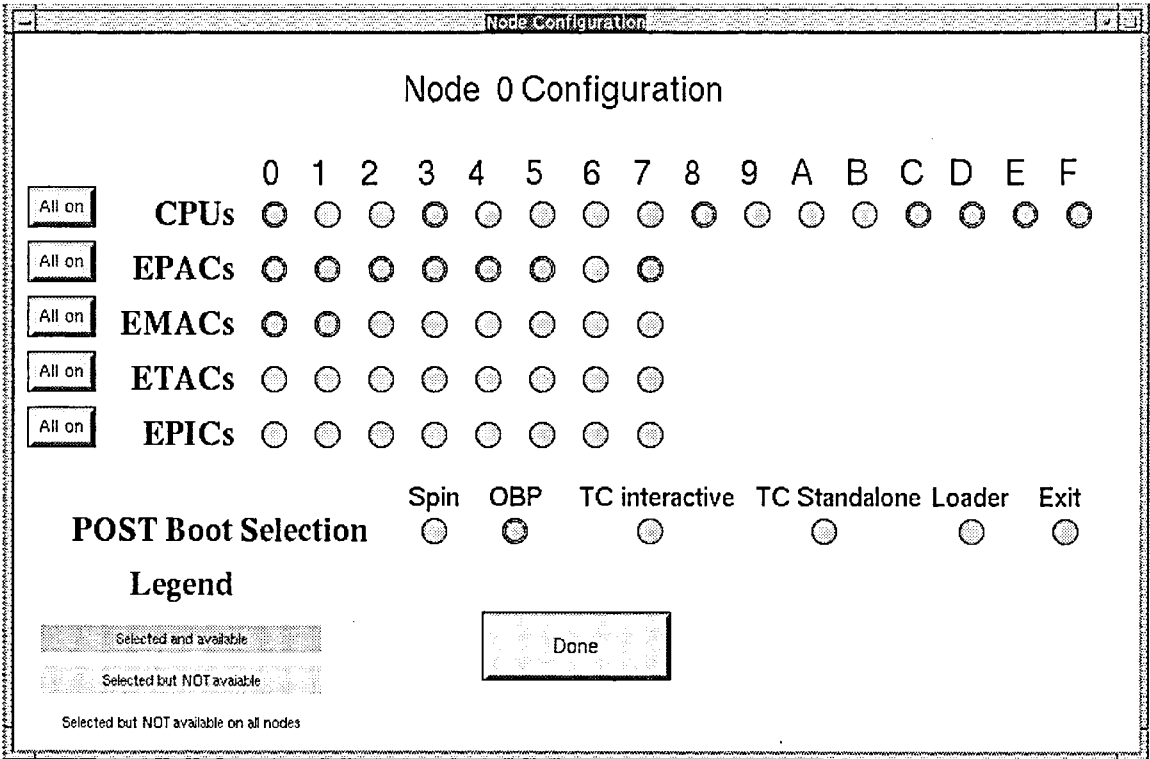


Figure 25 System configuration window

Help menu

The Help menu has two entries: About and Contents. The About selection displays the version number of `cxtest` running and the Contents selection opens a browser that can scroll through the help file.

Test menu

Selecting a test from the Test menu opens a window like the one in Figure 26. The Test menu varies depending on the tests loaded. If there is only one test loaded in EEPROM, then only one test appears in this window. The test names are presented as they appear in the EEPROM.

Selecting a test opens a window that displays all classes for the test. See Figure 26. Down the left hand side of the window are a column of round buttons, and down the right hand side of the window are two columns of buttons.

The left column of buttons allows the user to select all the subtests in the class with a single click. The button will turn yellow when selected.

The round buttons on the right hand side select subtests (opening another window for these choices) within that class. If only some of the subtests in a class are selected, then both the round buttons for that class turn yellow.

Consider the round button on the left as an indication that tests within the class have been selected and the round button on the right as an indication that only some of the tests have been selected, as opposed to all the tests of that class.

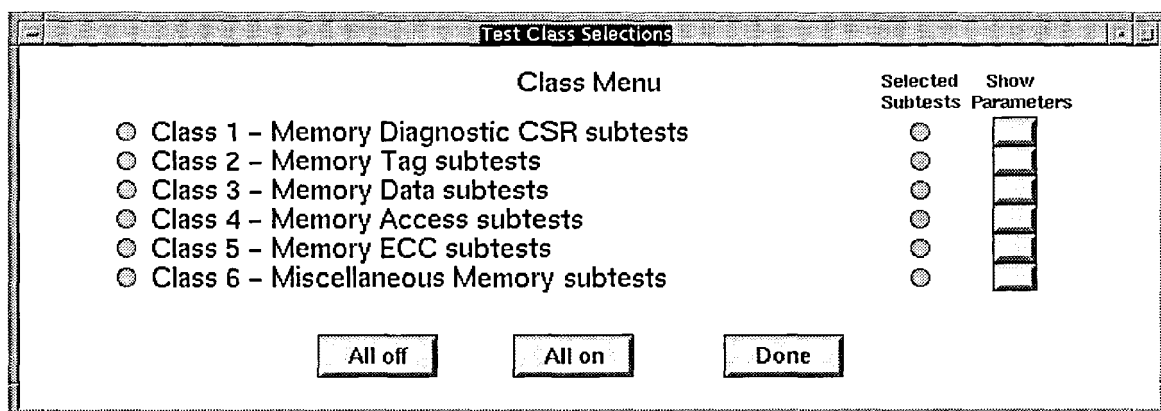


Figure 26 Test Class Selection menu

The last button on the right hand side associates parameters with the test class. Clicking this button opens another window with the parameters for that class. If there are more parameters than will fit on the screen, a scroll bar allows the user to scroll the list.

Also above and below each of the scroll bars are two buttons that allow the user to “page” up or down through the parameter list.

The Defaults button installs test default values into all the parameters.

If a class of tests has no parameters associated with it, the right most button (the square one) is not shown.

Display area

The display area shows the output of the tests. This output consists of messages that indicate when the tests start, the amount of time that the test has been running, and any error information.

The user can not cut and paste from this area. To record what transpires in test session, use the Log to File option.

When a test is started, a large ABORT button appears. Use this to escape out of a long test sequence or to stop a test not configured correctly. After using the ABORT button, reset the node from the Command menu. Once the abort command has been sent to the test controller, the button will disappear. The abort button also disappears when the test completes successfully.

Powering down the system

When using `ctest` in a troubleshooting environment, it is not necessary to exit and enter `ctest` each time the power is cycled.

To remove power to the system (for example, to move a board), power the system down leaving `ctest` running. Make sure that no tests are actively running.

Once power is restored, POST returns control to the test controller in the standalone mode. The user must also wait for the `cmd` routine to regenerate the database. A message will appear on the test station console stating the database generation is complete.

After the database is regenerated, the Boot Configuration map must be read using the Command menu. If this is not done, `ctest` will not have the correct hardware configuration information.

Command line interface

The command line interface allows scripting of a test sequence using any preferred shell or programming language.

All the options presented here are covered in the man page for `ctest`. The man page presents a complete list of all options. On the test station enter:

```
% man ctest
```

The command line interface also requires information be retrieved from the Utilities board. There is, therefore, overhead for starting the tests. It is recommended that the user test as much as possible on one command line before changing the configuration or margins. It is possible to specify more than one test on the command line and change the parameters for different tests as well.

Command line options

The command line should be built around the following model:

```
cxtest [loading options] <test> [parameters] [looping/pausing/control]
[class/subtest selections] <test> [parameters] [looping/pausing/control]
[class/subtest selections]...etc.
```

This model is described in the following sections.

Loading options

Table 8 shows the command line loading options.

Table 8 Command line loading options.

Loading options	Description
-f <load_file_name>	Use the <load_file_name> to read what tests are to be loaded in to cxtest .
-r	Force the information need for cxtest to be read from the EEPROM.
default	If no load options are specified, the file /spp/data/cxtest.load is read to know what tests to load.

Tests

Table 9 shows the tests that can be selected.

Table 9 Test Selection available in EEPROM

Test selections	Description
-cpu	Cpu3000 - tests only cpu module
-mem	Mem3000 - tests main memory
-arch	Arch3000 - tests architectural features
-io	Io3000 - tests io devices
-intra	Intra3000 - tests intrahypernode coherency
-inter	Inter3000 - tests interhypernode coherency

These tests are dependent on the code loaded in the EEPROM. The user is expected to know the classes and subtests for a specific test. One way to see what tests are available is to peek inside the class

and subtest data files mentioned in the "Speed ups" section on page 63.

Parameters

The user may specify the parameters for the test on the command line using the `-paXX <value>` switch, where `XX` is the parameter number (range 0-19) and `<value>` is the number for that parameter. These are specified on a test-by-test basis. As an example, the command line could look like:

```
% cctest -mem -pa1 0xffecccdd -c 5 -io -pa1 0x1234eeff -s 300
```

This is an example of how to set parameters.

See the man pages on each of the tests to know what value to set each of the parameters.

Looping/pause/control

Table 10 describes options that are available in the looping, pause, and control of `cctest`.

Table 10 Looping, pause, and control options

Looping/Pause/Controls	Description
<code>-pe <ON OFF></code>	Pause at end of subtest
<code>-pb <ON OFF></code>	Pause at beginning of subtest
<code>-ps <ON OFF></code>	Pause at beginning of class
<code>-pt <ON OFF></code>	Pause at end of class
<code>-ls <number></code>	Execute <number> of loops of the test that follows
<code>-lt <number></code>	Execute <number> of loops of all the tests that follow
<code>-t <number></code>	Switches the test controller to run on processor <number>. (range 0-15)
<code>-mt <number></code>	Allows specification of error count

One additional parameter, the `-t` option, is somewhat out of place, but it effects the control of the operation of the test and is, therefore, included.

Class and subtest selections

Table 11 shows the options used to select classes and subtests from a test.

Table 11 Class and subtest selections.

Class/subtest	Description
-c x,y-z	Class selections can be separated by commas and/or dashes. y-z indicates select class y through z. Selections separated by commas form a list.
-s yyy-zzz,xxx,vvv	Subtest selections can be separated by commas and/or dashes. y-z indicates select class y through z. Selections separated by commas form a list.
-x yyy-zzz,xxx	Exclude subtest selections can be separated by commas and/or dashes. y-z indicates select class y through z. Selections separated by commas form a list.
-y x,y-z	Exclude class selections can be separated by commas and/or dashes. y-z indicates select class y through z. Selections separated by commas form a list.

The test controller remains in the standalone mode after completing a command line execution of `ctest`. To return to the interactive mode of the test controller, press the TOC button on the system, and then exit the test controller, once the interactive menus have been displayed.

Test output

Test progress and error information is displayed just as in the graphics interface, with the exception that the information is displayed on the terminal the test was started from. There is no logging to a file with this interface, so the invocation of `ctest` should capture standard out and standard error into a file if the log is desired.

Speed ups

One mechanism for speeding up the invocation of `cxtest` is the load file.

By default the load file `/spp/data/cxtest.load` is read. This file might look like the following example:

```
/spp/data/arch3000.class
/spp/data/arch3000.subtest
/spp/data/cpu3000.class
/spp/data/cpu3000.subtest
/spp/data/io3000.class
/spp/data/io3000.subtest
/spp/data/mem3000.class
/spp/data/mem3000.subtest
/spp/data/intra3000.class
/spp/data/intra3000.subtest

end
```

The load file passes information about the tests in EEPROM to `cxtest`. If the user wishes only to load information about one test, the file should contain only those files that pertain to that test. Information in the `.class` and `.subtest` files have to match what is loaded in to the ROM. The files that are provided in `/spp/data` match the latest release of the tests. That is not to say that `cxtest` will not run if it does not have the correct file, just that if a subtest has been eliminated or added to the ROM information for a specific test, the disk version of the files may need to be updated also.

One way to speed up the start-up time is to make a copy of the `cxtest.load` file and just include the test of interest. Use the `-f <filename>` option for select a specific start-up test file.

If the user wants to force the information to be read from the Utilities board, the `-r` option must be used. This is true for both the command line and the graphics interfaces. This operation takes several minutes to complete.

See Table 8 for all the loading options.

Introduction

This chapter describes `mem3000`, a memory test for S-Class and X-Class systems. `mem3000` requires a node with a minimum of one processor with two memory boards.

The following test configuration parameters must be set in order for the test to properly execute:

- Memory boards (EMBs) must be installed in multiples of two.
- Only one EPB can be enabled per pair of EMBs.
- Only one EPB can be enabled per PAC.

To prevent false errors from being reported, the user must set up parameters 4, 5, and six to correspond to the actual memory configuration.

Classes and subtests

`mem3000` consists of a series of tests grouped together in classes beginning with verification of the most basic functionality and progressing toward more complex functionality. Each class is broken down into subtests which target specific functionality.

The following sections describe the classes and individual subtests.

Classes

mem3000 has six classes of tests shown in Table 12.

Table 12 mem3000 test classes

Class	Description
1	Verifies the operation of the diagnostic CSRs on each EMB.
2	Verifies the tag field.
3	Verifies the data field.
4	Verifies the various coherent and noncoherent transactions.
5	Verifies the ECC.
6	Verifies miscellaneous memory capabilities.

Classes 1, 4, 5, and 6 can be configured to test a single EMB. Classes 2 and 3 use memory interleave and thus test over the range of EMBs.

Subtests

The mem3000 subtests are listed in Table 13.

Table 13 mem3000 subtests

Subtest	Description
100	Verifies the diagnostic CSRs can be written and read.
101	Verifies the other EMAC CSRs can be written and read.
110	Verifies data can be written and read on each bank using the diagnostic CSRs.
120	Verifies ECC can be written and read on each bank using the dig CSRs.
130	Verifies the tag can be written and read on each bank using the dig CSRs.
140	Verifies memory lines on each bank can be initialized using the dig CSRs.
150	Verifies the first 32 memory lines of each EMB using various data patterns.

Table 13 mem3000 subtests—(continued)

Subtest	Description
200	Tag Bank Test.
210	Verifies the tag portion of a memory line using an addressing pattern.
211	Verifies the tag portion of a memory line using a byte uniqueness pattern.
230-238	Verifies the tag portion of a memory line using the MarchC algorithm and different patterns.
300	Verifies the memory lines on each bank can be written and read using coherent operations.
310	Verifies the data portion of a memory line using an addressing pattern using coherent operations.
311	Verifies the data portion of a memory line using a byte uniqueness pattern using coherent operations coherent operations.
330-338	Verifies the data portion of a memory line using the March C algorithm and different patterns.
400	Verifies loads and stores transactions to memory.
410	Verifies data flush transactions to memory.
420	Verifies noncoherent transactions to memory.
500	Verifies ECC single bit data and tag errors are detected, logged, and corrected.
510	Verifies ECC double bit data errors are detected and logged using coherent operations.
520	Verifies ECC double bit data errors are detected and logged using noncoherent operations.
530	Verifies that ECC errors are ignored when disabled.
600	Verifies the memory system detects and reports accesses to all illegal and/or invalid memory space.
610	Verifies the memory system detects and reports error conditions when the memory tag state is ERROR.
620	Verifies the various mode bits in the EMAC System Configuration register.
640	Determines whether 80-bit or 88-bit DIMMs are installed.

Subtests in classes 5 and 6 will produce HPMCs (indicated by the test controller printing the # character). These are expected.

User parameters

The test controller provides mem3000 with up to 20 user parameters. Current parameters are defined in Table 14.

Table 14 mem3000 test parameters

Words	Usage
0/1	64-bit user pattern 0 used in subtests 238 and 338 (defaults=0xa5a5a5a5/0xa5a5a5a5)
2/3	64-bit user pattern 1 in subtests 238 and 338 (defaults=0x5a5a5a5a/0x5a5a5a5a)
4	Last bank to test, inclusive (default=3)
5	Last row to test, inclusive (default=7)
6	Denotes 88-bit DIMMs are installed (default=1)
7	First bank to test, inclusive (default=0)
8	First row to test, inclusive (default=0)
9	Denotes if test is to run with errors disabled (default=0)

Using mem3000

The user can run mem3000 from either the test controller command line or from the cxtest window. The following sections show the user how to use mem3000, following the example scenario:

- Configure mem3000 to run on a system with four EMBs installed
- Set the classes and subset to be executed.
- Run the tests.
- View the results.

Configuration

To execute the scenario, perform the procedures in this and the following sections:

- Step 1** From the test controller main menu shown in Figure 27, select the Test Selection Menu, option A.

MAIN Menu commands

0=Quit Test Controller
1=Begin Test Controller Execution
2=Halt Test Controller Execution
3=Resume Test Controller Execution
4=Switch CPU
5=POST Boot Selection
6=Execution Mode Selection
7=Global Parameter Display
8=CPU Summary Display
9=Display CPU Errors
A=Test Selection Menu
B=Test Configuration Menu
C=Debugging Menu

Figure 27 Selecting Test Selection option from TC main menu

Step 2 From the Test Selection menu shown in Figure 28, select Memory test, option 1.

Test Selection Menu

1=*Memory test
2= Architecture Features test
3= Intra-Node Coherency test
4= Inter-Node Coherency test
5= I/O test
6= CPU Selftests
7= not available
8= not available
9= not available
A= not available

Figure 28 Selecting Memory test from Test Selection menu

This opens the Test Configuration menu.

Step 3 From the Test Configuration menu shown in Figure 29, select the Hardware Selection menu, option A.

```
Test Configuration Menu
0=Return to Main Menu          9=Display Test Parameters
1=Display Classes             A=Hardware Selection Menu
2=Display Subtests           B=Loop Enable
3=Select Classes             C=Loop Count
4=Select Subtests           D=Test Error Count
5=Read All Test Parameters    E=Pause at Test Start
6=Read One Test Parameters    F=Pause at Test End
7=Write Test Parameter       G=Pause at Subtest Start
8=Reset Parameters           H=Pause at Subtest End
```

Figure 29 Selecting Memory test from Test Selection menu

Step 4 From the Hardware Selection menu shown in Figure 30, select CPUs, option 1.

```
Test Configuration Menu - Hardware Selection
Display
0=Return to Test Configuration Menu
1=CPU Selection
2=EPAC Selection
3=EMAC Selection
4=ETAC Selection
5=EPIC Selection
6=Node Selection
```

Figure 30 Selecting CPUs from Hardware Selection menu

Step 5 At the following prompt:

```
Select CPUs: 0 2
```

Select the number of processors (CPUs).

After the number of processors is chosen, the Hardware Selection menu reappears.

Step 6 From this menu select Return to Test Configuration Menu, option 0.

From the Test Configuration menu, the user can select option 9 to view the changes.

Selecting classes and subtests

To select test classes and subtest, perform the following procedure:

- Step 1** From the Test Configuration menu, select Display Subtest, option 3.
- Step 2** From the following prompt, select the test classes:
Enter class number:
- Step 3** From the Test Configuration menu, select Display Subtests, option 2.

The subtest menu shown Figure 31 in lists all available subtests.

```
100* Diagnostic CSR Read/Write Test
101* Other EMAC CSR Read/Write Test
110* Memory Data Read/Write Test
120* Memory ECC Read/Write Test
130* Memory Tag Read/Write Test
140* Memory Initialization Test
150* First 32 Memory Lines Test
200* Tag Bank Test
210* Tag Addressing Test
211* Tag Byte Uniqueness Pattern Test
230* Tag March-C Pattern #1 Test
231* Tag March-C Pattern #2 Test
232* Tag March-C Pattern #3 Test
233* Tag March-C Pattern #4 Test
234* Tag March-C Pattern #5 Test
235* Tag March-C Pattern #6 Test
236* Tag March-C Pattern #7 Test
237* Tag March-C Pattern #8 Test
238* Tag March-C User Data Pattern Test
300* Memory Bank Test
310* Memory Addressing Test
311* Byte Uniqueness Pattern Test
330* Memory March-C Pattern #1 Test
331* Memory March-C Pattern #2 Test
    0xbfbfbfbfbfbfbfbf and
    0x4040404040404040
332* Memory March-C Pattern #3 Test
333* Memory March-C Pattern #4 Test
334* Memory March-C Pattern #5 Test
335* Memory March-C Pattern #6 Test
336* Memory March-C Pattern #7 Test
337* Memory March-C Pattern #8 Test
338* Memory March-C User Data Pattern Test
400* Memory Load/Store Test
410* Memory Data Flush Transaction Test
420* Memory Semaphore Transaction Test
500* ECC Single Error Correction Test
510* ECC Double Error Detection (coherent)
520* ECC Double Error Detection
    (non-coherent)
530* ECC Disable Test
600* Memory Access Protection Test
610* Memory Tag Test I
620* EMAC System Configuration CSR Test
640* 80 vs. 88 Bit DIMM Test
```

Figure 31 mem3000 Subtests menu

Step 4 Select all appropriate subtests. Table 15 lists the test patterns for subtests 230 through 238.

Table 15 Test patterns for subtests 230 through 238

Subtest	Patterns
230	0x7f7f7f7f7f7f7f7f 0x8080808080808080
231	0xbfbfbfbfbfbfbfbf 0x4040404040404040
232	0xdfdfdfdfdfdfdfdf 0x2020202020202020
233	0xefefefefefefefef 0x1010101010101010
234	0xf7f7f7f7f7f7f7f7 0x0808080808080808
235	0xfbfbfbfbfbfbfbfb 0x0404040404040404
236	0xfdffdfdfdfdfdfdf 0x0202020202020202
237	0xfefefefefefefefe 0x0101010101010101
238	0xa5a5a5a5a5a5a5a5 0x5a5a5a5a5a5a5a5a

Selecting Display Subtests, option 2, from the Test Configuration Menu reflects the changes.

Starting tests

To run the tests selected from the test controller main menu, select Begin test controller Execution, option 1. Figure 32 shows the output.

Error codes

When a failure is encountered, an event code is set along with an error message. The least significant 12 bits of the event code contain the error code. Table 16 lists the mem3000 error codes.

Table 16 mem3000 error codes

Code	Description
001	Diagnostic address CSR miscompare occurred (in upper 32-bits).
002	Diagnostic address CSR miscompare occurred (in lower 32-bits).
003	Diagnostic data CSR miscompare occurred (used only by class 1).
004	Diagnostic data CSR miscompare occurred (in upper 32-bits).
005	Diagnostic data CSR miscompare occurred (in lower 32-bits).
008	Miscompare occurred in the upper 32-bits of the CSR.
009	Miscompare occurred in the lower 32-bits of the CSR.
010	Memory data miscompare occurred.
011	Memory data miscompare occurred (upper 32-bits).
012	Memory data miscompare occurred (lower 32-bits)
013	Memory data matched when it shouldn't have (upper 32-bits).
014	Memory data matched when it shouldn't have (lower 32-bits).
020	Miscompare occurred in the upper 32-bits of the tag.
021	Miscompare occurred in the lower 32-bits of the tag.
022	The tag changed when it shouldn't have.
030	ECC data miscompare occurred.
031	An ECC error was logged when it shouldn't have been.
032	EMAC did not correct the single bit ECC failure as expected.
033	EMAC did not log the occurrence of a single bit ECC failure.
035	EMAC did not log the occurrence of a double bit ECC failure.
040	Data miscompare error occurred in sequence 1 of MarchC test (upper 32-bits).
041	Data miscompare error occurred in sequence 1 of MarchC test (lower 32-bits).
042	Data miscompare error occurred in sequence 2 of MarchC test (upper 32-bits).
043	Data miscompare error occurred in sequence 2 of MarchC test (lower 32-bits).
044	Data miscompare error occurred in sequence 3 of MarchC test (upper 32-bits).
045	Data miscompare error occurred in sequence 3 of MarchC test (lower 32-bits).
046	Data miscompare error occurred in sequence 4 of MarchC test (upper 32-bits).

Table 16 mem3000 error codes—(continued)

Code	Description
047	Data miscompare error occurred in sequence 4 of MarchC test (lower 32-bits).
060	A semaphore operation did not trigger.
070	Incorrect data returned for a semaphore operation.
080*	Incorrect info in EMAC error CSRs (single bit data ECC - read).
090*	Incorrect info in EMAC error CSRs (single bit tag ECC - read).
0a0*	Incorrect info in EMAC error CSRs (double bit data ECC - read).
0b0*	Incorrect info in EMAC error CSRs (double bit data ECC -coh_inc op)
0c0*	Tag state did not equal ERROR as it should have.
0d0*	Tag state did not equal INVALID as it should have.
0e0*	An unexpected error was detected in the EMAC error CSRs
100*	Uninstalled Memory.
110*	Invalid CSR.
120*	Network Cache
130*	Unprotected Memory.
140*	Alternate Interleave.
200	Denotes the EMB contains all 80-bit DIMMs.
201	Denotes the EMB contains all 88-bit DIMMs.
202	Denotes the EMB contains a mixture of 80-bit or 88-bit DIMMs are installed.

The asterisks next to the error codes listed in Table 16 actually indicate a range of events as shown in Table 17.

Table 17 Extended range for error codes

Code	Meaning
code+1	Error cause CSR miscompare error (upper 32-bits)
code+2	Error cause CSR miscompare error (lower 32-bits)
code+3	Error info CSR miscompare error in the error type field
code+4	Error info CSR miscompare error in the ENUM field
code+5	Error info CSR miscompare error in the cc/msg field
code+6	Error address CSR miscompare error (upper 32-bits)
code+7	Error address CSR miscompare error (lower 32-bits)
code+8	Error info CSR miscompare error in the syndrome field.

An error message can have one of four formats. The first format type is shown in Figure 34.

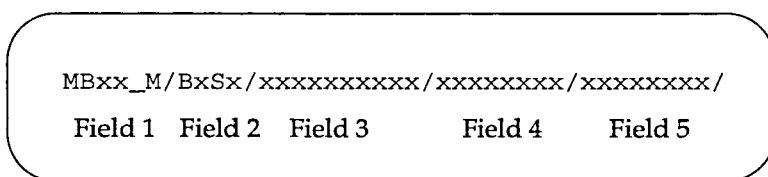


Figure 34 Error message format one

There are five fields separated by / symbols. Table 18 lists the meaning of each field.

Table 18 Error message field description for error format one

Field	Description
1	Specifies the EMB on which the failure was detected.
2	Specifies the DIMM on which the failure was detected.
3	Specifies the failing 40-bit address.
4	Specifies the actual 32-bits of data.
5	Specifies the expected 32-bits of data.

A second format type is shown Figure 35.

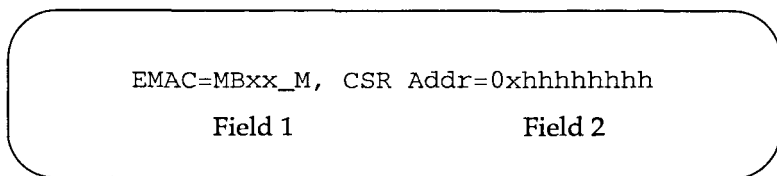


Figure 35 Error message format two

Table 18 shows the error message field description for this format.

Table 19 Error message field description for error format two

Field	Description
1	Specifies the EMB on which the failure was detected.
2	Specifies the failing 32-bit address of the CSR.

A third type of error format is shown in Figure 36. This format is used only by subtest 101 which tests the EMAC CSRs.

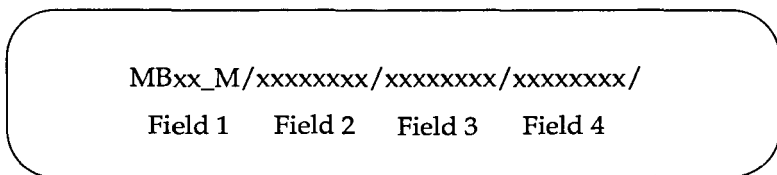


Figure 36 Error message format three

There are four fields separated by / symbols. Table 18 lists the meaning of each field.

Table 20 Error message field description for error format three

Field	Description
1	Specifies the EMB on which the failure was detected.
2	Specifies the failing 32-bit address of the CSR.
3	Specifies the actual 32-bits of data.
4	Specifies the expected 32-bits of data.

This chapter details most of the diagnostic utilities which include:

- `sppconsole`
- `hard_logger`
- `pce_util`
- `load_eprom`
- `load_mem`
- `tc_show_struct`
- RDR dump utilities
- Version utilities
- Event processing
- Miscellaneous tools

sppconsole

The `sppconsole` script invokes the `/spp/etc/console` program to provide the operating system a console interface. Refer to the `console(8)` manpage for more information about this program.

The `console` program connects to a server running on the test station. This server is called `conserver` (console server) and more information about it can be found in the `conserver(8)` manpage.

This interface communicates with the test controller, OBP, and operating system.

To start console interface, type the following command in a test station window:

```
% sppconsole
```

After making the connection, the last 20 lines of the console output are displayed.

All information and error messages are logged into the /usr/adm/syslog system error log file.

hard_logger

hard_logger is a script that invokes the interrogators and extractors to log all error information on a node

The usage of the script is:

```
hard_logger [node number]
```

[node number] is a hex number.

As an example, entering **hard_logger 0** runs hard_logger on node 0.

Entering **hard_logger** on the command line without arguments, invokes the hard_logger man page.

Two arguments, -h and -H, also invoke the hard_logger man page.

The hard_logger script performs the following tasks:

- Parses the command line arguments to determine on which node it should run
- Acquires COP information for the node using `ccmu cop $node` and saves the output to `/tmp/hl/COP_FILE_n$node`
- Acquires PCE information using `pce_util $node` and saves the output to `/tmp/hl/T_FILE_n$node`
- Checks the Stop On Hard bits of each PACs to find one that is running
- Reads MUC CSRs.
- Traverses the list of hard error buses. If a bus reports a hard error, then it performs the following:
 - Interrogates each controller on that bus for hard errors.
If the hard error group pin is set to a one value, it ignores the controller.
If the pin is a zero value, the controller may have been the first to record the error.
 - Interrogates the controller reporting the error.
To interrogate the controllers, hard_logger calls the asic-specific interrogator located in `/spp/scripts/<asic>`.
For example, the MAC interrogator is located in `/spp/scripts/emacs`
The interrogator returns a list of extractors to run on that asic in `/tmp/hl/inter_n$node`.
 - Runs each extractor returned by the interrogator

- Prints the results to STDOUT.
- Logs the results in /spp/data/hard_hist
hard_hist is a permanent file which records the date, time, and results of the script.

Since `STDERR` updates the user on progress and syntax errors and `STDOUT` contains user-readable output from the program, the output of `hard_logger` can be redirected to a file and saved.

pce_util

The `pce_util` utility performs the following:

- Resets the Utilities board
- Display status of the Utilities Board

It processes the command line in order from left to right, sending scan messages to the appropriate registers to perform the clock, power, or other environmental changes and/or to report current status.

The following describes `pce_util` usage:

```
pce_util [-C [number]] [-n N N N] [-d] [-b] [-s] [-c s (nue)] [-r X]
[-t X] [-l] [-p (lnu) 1 2 3 4 All]
```

Table 22 describes the `pce_util` options.

Table 22 `pce_util` options

Options	Description
C [number]	Displays the current complex name.
-n N [N...N]	Specifies the nodes for the <code>pce_util</code> commands.
-d	Displays the current state.
-b	Toggles the blinking state of the LED.
-s	Suppresses the output.
-c s[ource] [nue]	Manipulate clocks on the current nodes.
n[ominal]	Nominal frequency.
u[pper]	Upper frequency.
e[xternal]	External connector.
d[isplay]	displays current node status.
-l	Produce the long text description of state.
-t X	Set the TOC flag to X.

Table 22 pce_util options—(continued)

Options	Description
-r X	Set the Power flag to X.
-p [lnu] [1234 or All]	Manipulate power on the current nodes.

Note

Power supply 4 may not be present on all machines.

With no options, `pce_util` defaults to displaying the current clock, power, and environmental state for each node under test.

The power and clock setpoints are fixed in hardware, and can not be changed with this utility.

The `pce_util` utility normally returns a zero value, even if some voltages or temperatures are out of tolerance. If a serious error occurs, `pce_util` returns a nonzero value

The following are examples of how to use the `pce_util` utility and some of the output generated by it.

Figure 38 shows the output of the following command example.

```
% pce_util -n 0
```

```
pce_util:  new node list: 0
Complex name is Default_complex
Node Clocks          LEADS   @C U SHPT Supply 1 Supply 2 Supply 3 Supply 4
-----
0 Normal          ATTN 0x68   28 1 0000 Nominal  Nominal  Nominal  Nominal
```

Figure 38 Example of `pce_util` with `-n 0` options set

Figure 39 shows the output of the following command example.

```
% pce_util -n 0 -p n all
```

```
pce_util: new node list: 0
Complex name is Default_complex
Node Clocks          LEDS    @C U SHPT Supply 1 Supply 2 Supply 3 Supply 4
-----
0 Upper             0x00      27 1 0000    Lower    Lower    Lower    Lower
```

Figure 39 Example of `pce_util` with `-n 0 -p n` all options set

Figure 40 shows the output of the following command example.

```
% pce_util -n 0 -c s u
```

```
pce_util: new node list: 0
data is 1 to write clock
Complex name is Default_complex
Node Clocks          LEDS    @C U SHPT Supply 1 Supply 2 Supply 3 Supply 4
-----
0 Upper             0x00      27 1 0000    Lower    Lower    Lower    Lower
```

Figure 40 Example of `pce_util` with `-n 0 -c s u` options set

To disable the blinking LED caused by a failing power supply, use the following commands:

```
% pce_util -n0 -r1
```

```
% pde_util -n0 -r0
```

Figure 41 shows the output of the following command example.

```
% pce_util -l
```

```
pce_util:  new node list: 0
           Complex:      Default_complex
           node:         0
           clock margin: Normal
           LED display:   0x00
           Temperature:   26
           Hardware Status:
               Utility reset state: 1
               SOFT reset state  : 0
               HARD reset state  : 0
               48V Pwr reset state: 0
               TOC reset state   : 0
           Power Supply 1: Nominal
           Power Supply 2: Nominal
           Power Supply 3: Nominal
           Power Supply 4: Nominal
```

Figure 41 Example of pce_util with -l option set

load_eprom

The load_eprom utility resides on the test station platform. It downloads the core firmware products into the EEPROM on the Utilites board through the scan interface. It can also update the JTAG scan interface controller firmware. If, during a download, it detects any errors, it automatically retries the download.

The load_eprom utility uses subroutines that perform the following functions:

- It reads a raw binary file on the test station.
- It erases the specified Flash sector and verifies that the erase was successful. It will retry if the erase fails.
- It scan downloads the contents of the binary in 4096-byte page increments, updating the screen for each page. A "w" is printed during the write operation, an "r" during the optional read operation, a "v" during the optional verify operation and a "." when the page is complete.
- It can optionally read each page back for verification.
- It can read-verify a binary in the Flash EEPROM and compare it to the binary on the test station, without performing the write operation.

The load_eprom utility usage is as follows:

```
load_eprom -n <node> [-QRV] [-P #] [-j|c|e|p|o|t] <file>
```

The `-n <node>` specifies the target node name. The options available are given in Table 23.

Table 23 `load_eprom` options

Option	Description
<code>-Q</code>	Quiet (no) output mode.
<code>-R</code>	Read and verify data only-No writing.
<code>-P number</code>	EPAC to use for scan operations where number is 0-7, 8 is UBUS.
<code>-V</code>	Verify data after a write.
<code>-j <file></code>	Load binary into JTAG flash.
<code>-c <file></code>	Load binary into JTAG_CORE flash.
<code>-e <file></code>	Load binary into PDC Entry section.
<code>-p <file></code>	Load binary into PDC POST section.
<code>-o <file></code>	Load binary into PDC OBP section.
<code>-t <file></code>	Load binary into PDC Test Controller section.

As an example, entering the following reads the file `/spp/firmware/post.fw` and updates the POST section of Flash EEPROM on the Utilities board.

```
xns3_d% load_eprom -n mu_0000 -j jtag.fw
```

Entering the following reads the file `./jtag.fw` and updates the Flash EEPROM for the JTAG controller.

```
xns3_d% load_eprom -n mu_0000 -p /spp/firmware/post.fw
```

Figure 42 shows the output generated by using `load_eprom` in three ways. The first two writes to one sector in EEPROM and the last writes across several sectors.

```
% load_eprom -n mu_0000 -p entry.pdc

new_load_eprom                000.000.000.204 1996/11/27 13:57:39 done
Reading file "entry.pdc": 4253 (0x109d) bytes read.
Using default EPAC (POL).
Erasing sector 0 (0xf000000) OK
Writing sector 0 (0xf000000) .. OK

% load_eprom -n mu_0000 -p post.fw

new_load_eprom                000.000.000.204 1996/11/27 13:57:39 done
Reading file "post.fw": 92820 (0x16a94) bytes read.
Using default EPAC (POL).
Erasing sector 4 (0xf002000) OK
Writing sector 4 (0xf002000) ..... OK

% load_eprom -n mu_0000 -o obp.pdc

new_load_eprom                000.000.000.204 1996/11/27 13:57:39 done
Reading file "obp.pdc": 499712 (0x7a000) bytes read.
Using default EPAC (POL).
Erasing sector 7 (0xf008000) OK
Writing sector 7 (0xf008000) ..... OK
Erasing sector 8 (0xf00a000) OK
Writing sector 8 (0xf00a000) ..... OK
Erasing sector 9 (0xf00c000) OK
Writing sector 9 (0xf00c000) ..... OK
Erasing sector 10 (0xf00e000) OK
Writing sector 10 (0xf00e000) ..... OK
```

Figure 42 Example of `load_eprom` output

While `load_eprom` is writing a block of data, a "w" is printed. If the write is successful, a dot is printed. The dots continue until the whole sector is successfully written, at which time the "OK" is printed.

load_mem

The load_mem utility loads files or raw data into memory. It can be used in the absence of any other program loading device.

Utility usage is as follows:

```
load_mem <filename> [-check] [-n <node number in hex>] [-r <ring  
number in hex>] [-raw] [-sa <starting address>] [-ea <ending address>]  
[-h] [-help]]
```

<filename> must be present for loading. The file is loaded using calls to scn_mem_wr.

Table 24 shows the options for load_mem.

Table 24 load_mem utility options

Option	Description
-check	Enables checking of written data via calls to scn_mem_rd.
-n <hex number>	Indicates which node to access.
-p <hex number>	Indicates which EPAC to use. If not specified, get_default_pac generates the ring number.
-raw	Indicates that <filename> is a raw binary. If this option is used, the starting and ending addresses must also be provided.
-sa <hex number>	Indicates the starting address for placement of the raw binary: <filename>.
-ea <hex number>	Indicates the ending address for terminating the raw binary: <filename>.
-s <hex number>	Specifies the size in words of the raw binary.
-help	Display the help file and prompt user for list of error codes.
-h	Any word that begins with an h displays help file.

The user can call load_mem on an a.out type file. It uses the series 700/800 implementation of a.out.h to correctly parse and load the file.

The ending address is the next address after the end of where the raw binary is loaded. The starting and ending addresses must be formatted for excalibur addressing and read in full words.

tc_show_struct

The `tc_show_struct` tool examines certain structures that the test controller uses to set up and run tests. The structures examined are:

- `tc_global_parameter_struct`
- `tc_test_info_struct`
- `tc_cpu_info_struct`

The `tc_test_info_struct` structure displays the following fields:

- The entry point
- Class pointer
- Subtest pointer
- Hardware requirements
- Test specifics
- Parameter pointer
- HW requirements met
- Test initiated
- Test selected
- Run classes
- Run subtests

The `tc_global_parameter_struct` structure displays the master state.

The `tc_cpu_info_struct` structure displays the status or state of each processor and the current subtest.

The `tc_show_struct` tool takes two arguments: the first is the test of interest, the second is the node of interest.

Possible selections for the test are:

- `-mem`
- `-io`
- `-inter`
- `-intra`
- `-cpu`
- `-arch`

An example of the output is shown in Figure 43.

```

exhmu4_d% tc_show_struct -io
1 Nodes found
-----
Name : io3000 - EEPROM based I/O tests
Entry Pt      ClTb ptr      StTb ptr      HwReq      ParmTbptr      Parm_ptr
-----
0xf01c8000    0xf01c806c    0xf01c8f60    0xf01c8064    0xf081c2e8    0xf0808438
-----
Hardware req met = 1 | Test initied   = 1
Selected = 1         | TC State = TC_RUNNING
-----
Class[0]   = 0      Subtest[0] = 645
Class[1]   = 0      Subtest[1] = 0
Class[2]   = 0      Subtest[2] = 0
Class[3]   = 0      Subtest[3] = 0
Class[4]   = 0      Subtest[4] = 0
-----
Current Values for Parameters
00) 0x00000000 01) 0xf0000000 02) 0x00000000 03) 0x00000000
04) 0x00000000 05) 0x00000001 06) 0x00000000 07) 0x00000000
08) 0x10405090 09) 0x105050a0 10) 0x116051b0 11) 0x118051c0
12) 0x0ff00ff0 13) 0x0ff00ff0 14) 0x0ff00ff0 15) 0x0ff00ff0
16) 0x0ff00ff0 17) 0x0ff00ff0 18) 0x0ff00ff0 19) 0x0ff00ff0
-----
CPU Mask = 0x0a0a    EPAC Mask = 0xff
EMAC Mask = 0xc3     ETAC Mask = 0x00
EPIC Mask = 0x33
-----
CPU 0 - State - TC_CPU_NOT_AVAIL      Subtest 0
CPU 1 - State - TC_CPU_DONE           Subtest 645
CPU 2 - State - TC_CPU_NOT_AVAIL      Subtest 0
CPU 3 - State - TC_CPU_DONE           Subtest 645
CPU 4 - State - TC_CPU_NOT_AVAIL      Subtest 0
CPU 5 - State - TC_CPU_NOT_AVAIL      Subtest 0
CPU 6 - State - TC_CPU_NOT_AVAIL      Subtest 0
CPU 7 - State - TC_CPU_NOT_AVAIL      Subtest 0
CPU 8 - State - TC_CPU_NOT_AVAIL      Subtest 0
CPU 9 - State - TC_CPU_DONE           Subtest 645
CPU 10 - State - TC_CPU_NOT_AVAIL     Subtest 0
CPU 11 - State - TC_CPU_DONE          Subtest 645
CPU 12 - State - TC_CPU_NOT_AVAIL     Subtest 0
CPU 13 - State - TC_CPU_NOT_AVAIL     Subtest 0
CPU 14 - State - TC_CPU_NOT_AVAIL     Subtest 0
CPU 15 - State - TC_CPU_NOT_AVAIL     Subtest 0

```

Figure 43 Example of tc_show_struct output

RDR dump utilities

This set of utilities allows the user to dump, format, and display the RDR state within a processor. They reside in the `/spp/unsupported` directory and consist of the following:

- `rdr_dumper.fw`
- `rdr_formatter`
- `scan_sram`

The following procedure reads, formats, and displays RDRs:

- Step 1** In the test controller window, select POST Boot Selection option from the main menu.
- Step 2** Select the Dumper option and press **Return**.
- Step 3** Exit the test controller by selecting Main menu option 0. This resets the system. When POST displays “Booting RDR Dumper,” wait approximately 10 seconds for the `rdr_dumper` utility to complete. As an alternative, read the four words starting at location `0xf0804000` via `sppdsh`. As each processor completes, it sets its corresponding byte in this array.
- Step 4** Run the `/spp/unsupported/scan_sram` script. This script scans the dumped data into files kept in the `/tmp` directory. Instead of executing the entire script, you may execute only those lines for the processors under test by copying those particular lines from this script into a `sppdsh` shell.
- Run the `rdr_formatter` utility on the desired file as follows:
- ```
/spp/unsupported/rdr_formatter /tmp/cpuX.dump
```
- where X is the cpu ID 0-F.
- This dumps output to `STDOUT` which can be redirected to a file.
- Step 5** Press the node TOC button or type the `assert_toc 0` command in an `sppdsh` window. This resets the system and returns the system to the OBP prompt.

---

## Version utilities

This section describes the three version utilities.

---

### **diag\_version**

The `diag_version` utility displays the product name and the version of the current Exemplar Diagnostic package. For example:

```
$ diag_version
```

```
Exemplar Diagnostics, Version 1.0.1.0
```

---

## flash\_info

`flash_info` is a utility that probes the contents of the EEPROM on the Utilities board and displays the product name, version number, author, and date the product was built.

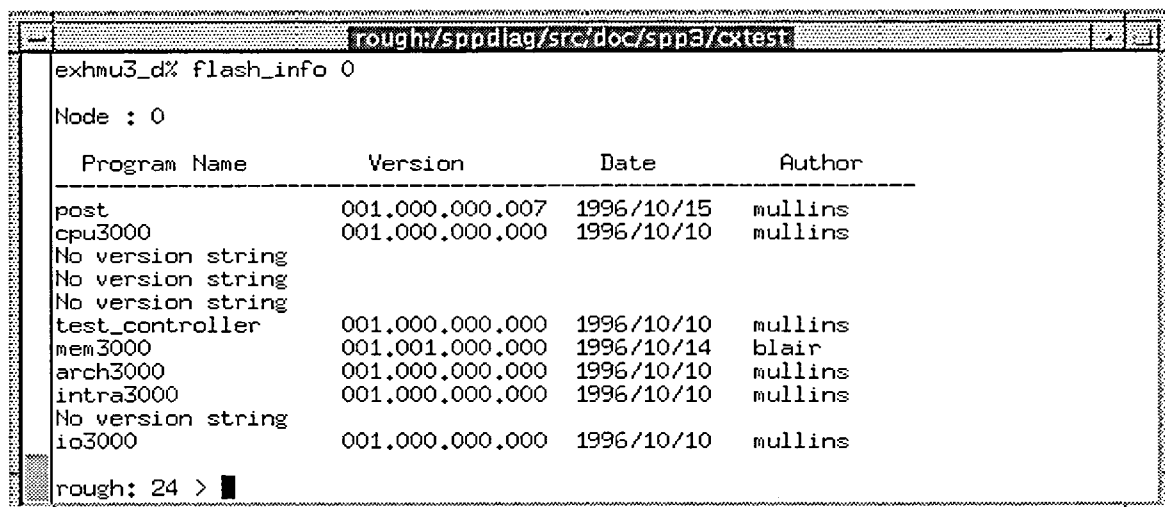
It needs only one argument, the node number of the Utilities board to be examined. If `flash_info` is used without an argument, the first node found (from `ccmd`) is the node queried.

The entrypoints of the standard products are checked for the *magic header*. If no magic header is found, the product is assumed not to be loaded. The one exception is OBP.

OBP does not have the magic header. Therefore, no information can be interpreted from `flash_info` with respect to OBP.

The entrypoints are checked in the order that they appear in the ROM.

An example of the output is shown in Figure 44.



```
rough/sppdiag/src/doc/spp3/ctest
exhmu3_d% flash_info 0
Node : 0
 Program Name Version Date Author

post 001.000.000.007 1996/10/15 mullins
cpu3000 001.000.000.000 1996/10/10 mullins
No version string
No version string
No version string
test_controller 001.000.000.000 1996/10/10 mullins
mem3000 001.001.000.000 1996/10/14 blair
arch3000 001.000.000.000 1996/10/10 mullins
intra3000 001.000.000.000 1996/10/10 mullins
No version string
io3000 001.000.000.000 1996/10/10 mullins
rough: 24 > █
```

Figure 44 Example of `flash_info` output

---

## ver

`ver` is a test station version retriever utility. It is used to read and display the version information built into each diagnostic product. Its usage is:

```
ver <file>
```

ver searches the specified file for a version string and extracts and displays the version and date stamp, as shown in the following example:

```
% ver test_controller
```

```
PDC test_controller 001.004.000.017 1997/03/12 15:06:12 blair
```

---

## Event processing

This section discusses three event processing utilities:

- event\_logger
- event\_browser
- log\_event

---

### event\_logger

event\_logger is an RPC server that takes requests, (events) and writes them into the event\_log file(/spp/data/event\_log). Event\_logger also can become a client to other programs that want to receive events and operate on them; an example is CERS.

There are two sources for events: a compiled program on the test station and the operating system. The mechanism for receiving the events is a little different, but once they are received, the events follow the same path.

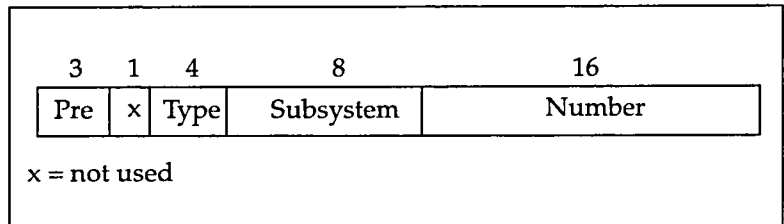
event\_logger is a daemon process and should never terminate. If it does so, the test station will spawn a new copy. There is a 25 second wait between starting the program and becoming a daemon and being able to receive events. This delay simplifies problems when the program is started by init after a reboot of the test station.

Events generated by compiled programs on the test station use a library call log\_error to establish the RPC link and send the event. In the case of the operating system events, event\_logger accepts UDP datagrams and formats them into an event. This implies that for operating system events, it is possible to miss an event since there is no guarantee of connection with UDP.

The event log itself is a plain text file that can be examined with any paging or editing tool. When the event log reaches one MByte in size, the file is closed, copied over to event\_log.old and compressed. A new event log is then opened. This preserves the history of events.

The event\_logger has only one option, the -d option that prevents the event\_logger from becoming a daemon, so the debugger can attach and start the program.

The format of the 32-bit event code is shown in Figure 45



**Figure 45** 32-bit event code format

The fields of the event code format are defined as follows:

- *Pre* field—Preamble that indicates severity of the event.
- *Type* field— source of the event (e.g. a utility or the kernel).
- *Subsystem* field—Qualification of what sent the event
- *Number* field—Unique identifier for a particular event (for example, power failing).

Table 25 gives the values of the preamble fields in the event code.

**Table 25** Values for the preamble field in the eventcode

| Values | Meaning   | Description                                         |
|--------|-----------|-----------------------------------------------------|
| 0      | Normal    | Request complete - no abnormalities).               |
| 1      | Debug     | Used for debugging.                                 |
| 2      | Info      | Informative.                                        |
| 3      | Warning   | Request successful, but no normal (example: retry). |
| 4      | Error     | Request was unsuccessful, but contained.            |
| 5      | Critical  | Conditions with possible widespread consequences.   |
| 6      | Emergency | Requires external intervention.                     |
| 7      | Panic     | Last gasp.                                          |

Table 26 gives the values for the type field in eventcode.

**Table 26** Values for type field in eventcode

| Values | Meaning      | Description                           |
|--------|--------------|---------------------------------------|
| 0      | Unknown      | Source is unknown.                    |
| 1      | Firmware     | Source is OS firmware type.           |
| 2      | Microkernel  | Source is from the kernel.            |
| 3      | Server       | Source is from a server.              |
| 4      | Unix utility | Source is from a utility.             |
| 5      | TS diags     | Source is a test station diagnostic.  |
| 6      | Node diags   | Source is processor-based diagnostic. |
| 7      | MU firmware  | Source is the MU firmware.            |

Table 27 gives the values for the subsystem field in the eventcode.

**Table 27** Values for the subsystem field in the eventcode

| Value | Description                                 |
|-------|---------------------------------------------|
| 0x40  | Miscellaneous MU firmware originated        |
| 0x41  | HP T-chip SW                                |
| 0x42  | Other Primary load T-chip SW                |
| 0x43  | Other Diag T-chip SW                        |
| 0x44  | TS communication SW                         |
| 0x45  | Diagnostic clock controller related         |
| 0x46  | Diagnostic scan related                     |
| 0x47  | Diagnostic config related                   |
| 0x48  | Diagnostic memory op related                |
| 0x49  | Diagnostic miscellaneous abnormal condition |
| 0x4a  | Diagnostic utility related                  |
| 0x4b  | Diagnostic test related                     |
| 0x4c  | Power/environmental related                 |
| 0x4d  | CXTS                                        |

**Table 27** Values for the subsystem field in the eventcode

| Value | Description          |
|-------|----------------------|
| 0x4e  | CERS                 |
| 0x4f  | PDC firmware related |

---

## event\_browser

`event_browser` is a text based utility that reads events from either a default or specified event log and displays the ones that meet the specified criteria to `stdout`. It has the following format:

```
event_browser [-D] [-a ``time"] [-b ``time"] [+/-c number [number...]]
[+/-e number [number...]] [-f <log file>] [+/-g ``phrase"] [-i] [+/-l
number [number...]] [-n] [-q] [-r] [+/- s number [number...]] [+/-t
number [number...]] [-v]
```

`event_browser` has a command line and an interactive mode. All options may be executed from either interface. In command line mode, the options specified on the command line are evaluated, then a report is generated, followed by `event_browser` terminating. In interactive mode, `event_browser` prompts for additional lines of commands (generating a report after each line), rather than exiting.

Interactive mode is entered by including `-i` on the command line. Options hold their value across reports unless changed or reset.

Table 28 shows the `event_browser` options.

**Table 28** `event_browser` options

| Option                                | Description                                                                   |
|---------------------------------------|-------------------------------------------------------------------------------|
| <code>-D</code>                       | Increment debug flag - for development use only.                              |
| <code>-a ``time"</code>               | Display only events occurring after this time.                                |
| <code>-b ``time"</code>               | Display only events occurring before this time.                               |
| <code>+c number</code><br>[number...] | Display only events with the specified condition codes (32 bits) [up to 256]. |
| <code>-c number</code><br>[number...] | Display all events except those with the specified condition codes (32 bits). |
| <code>-d</code>                       | Display differences in event times.                                           |

**Table 28** event\_browser options—(continued)

| Option                   | Description                                                                                    |
|--------------------------|------------------------------------------------------------------------------------------------|
| +e number<br>[number...] | Display only events with the specified event numbers (16 bits) [up to 256].                    |
| -e number<br>[number...] | Display all events except those with the specified event numbers (16 bits).                    |
| -f <log file>            | Read events from this log file.                                                                |
| +g ``phrase"             | Display only events that contain the specified phrase.                                         |
| -g ``phrase"             | Display all events except those that contain the specified phrase.                             |
| +i                       | Interactive mode - the log is not read initially and additional commands are read from stdin.  |
| -i                       | Interactive mode - additional commands are read from stdin.                                    |
| +l number<br>[number...] | Display only events with the specified severity field values.                                  |
| -l number<br>[number...] | Display all events except those with the specified severity field values.                      |
| +n                       | "sniff" starting at the end of the log. It ignores existing events. <b>Ctrl-C</b> stops sniff. |
| -n                       | "sniff" the end of the log when reached. <b>Ctrl-C</b> terminates sniffing.                    |
| -q                       | Terminate execution, the current line is not processed.                                        |
| -r                       | Reset severity, type, subsystem, and event sniff options (to all events).                      |
| +s number<br>[number...] | Display only events with the specified subsystem values [up to 256].                           |
| -s number<br>[number...] | Display all events except those with the specified subsystem values.                           |
| +t number<br>[number...] | Display only events with the specified type field values [up to 256].                          |
| -t number<br>[number...] | Display all events except those with the specified type field values.                          |

Several of the options allow for two ways of displaying the information: either "all except the specified" or "the specified only."

A minus sign (-) causes all events except those specified to be accepted, and a plus sign (+) causes only those events with the particular characteristic to be accepted. The options are mutually exclusive.

Only the last specification for each field applies. When a date is specified, the form should be the same as used in the event message, for example ``Wed Dec 16 14:07:30 1992.'' If any part of a date is missing, the missing parts will be extrapolated from the previous setting.

When in interactive mode, `event_browser` reads a line from `stdin` and processes it as if it were a command line (minus the executable name). After the options on each line are processed, a report is generated. If the `-n` option is specified, the log is "sniffed" until a `Ctrl-C` is received (at which time sniffing terminates). A `-quit` causes sniffing to terminate without processing any further options.

`event_logger` returns a zero value if no error was detected, and a nonzero value if a fatal error occurred. Nonfatal errors result in a message being printed to `stdout`.

---

## **log\_event**

`log_event` accepts input from standard in and packages it into an event. The event number is specified in one of three ways:

- Command line
- First line of the input
- Default

`log_event` is used by scripts such as the interrogators and extractors to put information into the event log as follows:

```
log_event [-c] [number]
```

If the `-c` option displays event information output on the console as well. If the event severity is high enough, this happens automatically. `event_logger` displays any events that have a severity greater than the warning level.

The following two examples show how `log_event` can be used:

```
cat data_file | log_event 0x86340001
```

This example puts an event in the event log with the event code of 0x86340001. The data will be the information contained in the file `data_file`.

```
echo "This is a test event" | log_event
```

This example puts the message "This is a test event" in the event log with the default event code from `log_event`.

---

## Miscellaneous tools

The following miscellaneous tools are described in this section:

- `ds1620`
- `ecc_calc`
- `kill_by_name`

---

### ds1620

The `ds1620` utility reads from or writes to the temperature sensing device. This utility determines when the system should shut down due to an over-temperature condition.

The following is the usage of this utility:

```
ds1620 [-h] [-n node number | All] [-q] [-c] [-b] [-e] [-s <l T>|<h T>|<c X>]
```

The following produces a help message displaying all commands:

```
ds1620 -h
```

The following produces the node number, the temperature, and the set points with a description. The `-q` option prints the results without the header:

```
ds1620 -n [number or All] [-q]
```

The following sets all nodes lower set point to T (temperature) and displays the results:

```
ds1620 -n [number or All] [-q] -s l T
```

The following sets nodes higher set points to T and displays the results:

```
ds1620 -n [number or All] [-q] -s h T
```

The following sets nodes higher set points to X and displays the results:

```
ds1620 -n [number or All] [-q] -s c X
```

The following reads the configuration register:

```
ds1620 -n [number or All] [-q] -c
```

The following starts temperature monitor mode:

```
ds1620 -n [number or All] [-q] -b
```

The following ends the temperature monitoring mode and displays the results:

```
ds1620 -n [number or All] [-q] -e
```

---

## **ecc\_calc**

`ecc_calc` is a calculator that accepts hex input and calculates the error correction code (ECC) value for that data. It is presently written to work on full 88-bit memory lines but can be used for single node (80-bit) data as well. To calculate ECC on 80-bit data, enter zeros for the last byte of data.

An example of the use of this script is shown below:

```
$ecc_calc
enter data[8:87]: 0123456789
 ecc_low_out = 'h 2c
 ecc_high_out = 'h 69
 ecc_out data[0:7] = 'h 45
enter data[8:87]:
```

To exit this utility, type `q`.

---

## **kill\_by\_name**

The `kill_by_name` script kills processes by name rather than by process identification. The following is the usage of this script:

```
kill_by_name <file name> <signal to send> <process id to not kill>
```

Table 29 describes the options in `kill_by_name`.

**Table 29** `kill_by_name` options

| Option                 | Description                                                                       |
|------------------------|-----------------------------------------------------------------------------------|
| file name              | Process name to kill.                                                             |
| signal to send         | Default is kill command.                                                          |
| process id to not kill | Kills all processes the match the specified name except the one matching this ID. |

If the third argument is used, the second argument must also be specified. For example:

```
kill_by_name foo 15 1234
```

---

## cbus

The `cbus` utility performs read, write, and erase operations on the core logic address space. All addresses are 32-bit in hexadecimal format. The format of this command is:

```
cbus -n <number> -p <number> [-r <addr> | -e <addr> | -w <addr> <data>]
```

Table 30 lists the `cbus` options.

**Table 30** `cbus` options

| Option           | Description                                             |
|------------------|---------------------------------------------------------|
| -n <number>      | the node to use                                         |
| -p <number>      | the EPAC to use                                         |
| -r <addr>        | reads and displays the data at the specified address    |
| -e <addr>        | erases the sector at the specified address              |
| -w <addr> <data> | writes the 32-bit data value into the specified address |

An example is as follows:

```
$ /spp/unsupported/cbus -n 0 -p 0 -r 0xf0d00000 0xfebfff
```

---

## fix\_boot\_vector

This `sppdsh` script restores the four words at the beginning of NVRAM to point to POST. These four words are used by the ENTRY firmware to determine which process was executing last when an HPMC, TOC, or reset occurs.

---

## stop\_on\_hard

This `sppdsh` script allows the user to enable, disable, and check the stop-on-hard bit in the option ring. Its usage is as follows:

```
stop_on_hard <node number> <on|off|chk>
```

where <node number> is zero.

The output of the `chk` option is shown in.

```
EPACs: p0l=0xff p1r=0x0 p2l=0x0 p3r=0x0 p4l=0x0 p5r=0x0 p6l=0x0 p7r=0x0
ERACs: r0l=0x0 r2r=0x0 r3r=0x0 r1l=0x0
EMACs: mb0l_m=0x0 mb1l_m=0x0 mb6r_m=0x0 mb7r_m=0x0
EPICs: iolf_b=0x0 iolf_a=0x0
ETACs:
```

**Figure 46** Output from `stop_on_hard` with `chk` option

A value of `0x80` denotes that stop-on-hard is enabled whereas a `0` denotes that it is disabled.



The Excalibur scan test (`est`) is a diagnostic utility that uses the system scan hardware making it possible to perform connectivity tests and to test gate array internals. The `est` utility runs on the optional test station and sends scan instructions to a given node via Ethernet.

---

## est utility test environment

`est` is started on the teststation and is located in `/spp/bin/est`. The user has the option of either starting up a user interface or having the `est` utility run a script.

`est` works on one node at a time by sending scan instructions and data and receiving the results over the diagnostic ethernet connection.

Since `est` has to communicate closely with the Utilities board, other diagnostics can not be run at the same time. Also, while `est` is moving data through the scan rings, the operating system can not be running.

---

## Running est

The following is the command line usage for `est`:

```
est [-options] <node_number>
```

For example, to test node 0, enter:

```
% est 0
```

`est` reads configuration information from files stored in `/spp/data` (e.g `node_0.cfg`). These configuration files are automatically generated by `ccmd` each time the system is powered up. While `ccmd` is running, it prints its status to the console window. When database generation is complete and no errors were reported, it writes the necessary configuration files and `est` may be executed.

Table 31 shows `est` command line options.

**Table 31** `est` command line options

| Option                           | Description                                  |
|----------------------------------|----------------------------------------------|
| <code>-v</code>                  | Print version and exit.                      |
| <code>-f &lt;filename&gt;</code> | Run a given script file.                     |
| <code>-l</code>                  | do not generate a log file.                  |
| <code>-o &lt;filename&gt;</code> | Redirect the log file to the given filename. |

Some examples of `est` usage are:

```
est -v
```

```
est -l -f my_script 0
```

```
est -o ./my_log_file 0
```

The `est` utility relies on certain data and vector files located in the `/spp/est` directory.

Unless disabled or redirected, the `est` utility will generate a log file, `est.log`, and store it `/spp/data/est.log`. Any previous log file will be renamed to `est.log.old`

Figure 47 shows an example of output using est.

```
% est mu_0000 0
Excalibur Scan Test Vr. 0.17.0 28-AUG-96 Steven Terry
sdp_send: node = start, fd = 4

REQUEST:
 1100800d 10010009 089a786e 73315f64
 00
fragment 1 of 1
sequence: 0
bytes: 13
compression flag : 0
response flag: 1
Utility Command
Utility command: reserve hw
sdp_rcv: node = start, fd = 3

RESPONSE:
 11000000 8002e000
fragment 1 of 1
sequence: 0
status: 0
bytes: 2
compression flag : 0
data:
 e000
.....
.....Memory Group: design
 11 Memory blocks manage the allocations
 2883573 Bytes alloc'ed from the system
 2751176 Bytes (95 %) used by the program

General EST Tests:
a ... board level ac tests
d ... board level dc tests
g [[dev file [limit]] ... gen_ga_patterns()
sso dev ... sso test for a given device

Special Scan Tests:
b ... bypass/id test
c ... compare id's to config file
i ... print id's found in design

EST Options:
D ... design query menu
F ... set option & debug flags
Q ... quit, not so nice
q ... quit nicely
h ... print this help message
v ... print EST version info
!cmd ... send the command to Unix (ex. "!ls patterns")
```

Figure 47 Example of est output

---

## est tests

est works on the JTAG scan rings throughout the system. Tests provided are:

- Ring (test command `r`)—Moves data through the scan rings to make sure the rings are connected and that basic scan hardware is operational.
- DC connectivity (command `d`)—Checks that wires on the boards between scan devices are intact (no shorts or opens).
- AC connectivity (command `a`)—Examines wires on the boards. AC tests look for timing problems between parts at full speed. If DC connectivity patterns passed, but AC connectivity failed, the failure is bound to be timing related.
- Gate array (command `g`)—Executes scan tests internal to selected arrays. When these tests fail, the array usually has to be replaced.

These tests are listed in the order in which they should normally be run.

---

## est commands

The est commands are described in the following sections.

---

### AC Connectivity test

The AC Connectivity test format is:

`a [-s -p #]`

Table 32 shows the options for the this test.

Table 32 AC Connectivity test options

| Option                         | Description                     |
|--------------------------------|---------------------------------|
| <code>-s</code>                | Step mode (for debug purposes). |
| <code>-p &lt;number&gt;</code> | Run pattern number only.        |

---

### Bypass test

The Bypass test format is:

`b`

The Bypass test places the scan ring hardware into bypass mode.

---

## DC Connectivity test

DC Connectivity test format is:

```
d [-s -p #]
```

Table 32 shows the options for the this test.

**Table 33** DC Connectivity test options

| Option      | Description                     |
|-------------|---------------------------------|
| -s          | Step mode (for debug purposes). |
| -p <number> | Run pattern number only.        |

---

## Gate Array test

The Gate Array test format is:

```
g [options] [pattern file]
```

Table 34 shows the options for the this test.

**Table 34** Gate Array test options

| Option       | Description                                                                   |
|--------------|-------------------------------------------------------------------------------|
| -r <refdes>  | Test arrays with matching a reference designator value.                       |
| -b <board>   | Test arrays on given board. <board> may either be a number or a name.         |
| -j <jtag_id> | Test arrays matching a jtag_id.                                               |
| -t <type>    | Test an array type (For example, RAC).                                        |
| -s <number>  | Start with a given pattern number.                                            |
| -e <number>  | End on a certain pattern number.                                              |
| -m <number>  | Run a maximum of <number> patterns per file.                                  |
| -o <number>  | Optimization level (0, 1, or 2) Two is the most optimized and is the default. |

By default, the `g` command tests all arrays. When the `-r`, `-b`, `-j`, or `-t` options are used, only arrays that meet all criteria are tested.

Gate array tests use test vectors that have been pregenerated for the certain arrays (each array has multiple files associated with it). The `-s`, `-e`, and `-o` options can be used to limit the number of patterns that are run for each pattern file. The default is to run all

patterns in each file. While it may take more time to run all patterns, using options to limit the number of patterns may result in a significant loss of test coverage.

The `-o` option controls either run time optimization or how much parallelism takes place. There are three levels:

- 0—No optimization
- 1—Same parts on the same ring are tested together
- 2—Identical rings are tested in parallel

If an error is encountered during parallel testing, the following message may appear:

```
*** errors found - must switch to serial testing ***
```

When an error occurs, parallel scans into the scan hardware may result in bus conflicts on TDO pins. Therefore, `est` automatically stops using parallel scans when errors happen.

---

## SCI test

`sci` is a utility that tests the Coherent Toroidal Interface (CTI) cables between nodes. The term SCI (Scalable Coherent Interface) is often used in place of the term CTI; the terms are interchangeable.

The usage of `sci` is as follows:

```
sci [driver] [receiver] ring test
```

where:

[driver]

Refers to the node and memory board to which the CTI cable is connected and from which the test data originates.

[receiver]

Refers to the node and memory board to which the other end of the CTI cable is connected and receives test data.

ring

Refers to the CTI ring associated with the cable, either x or y.

test

Refers to the specific test: `dc`, `dc_clk`, `ac`. With the `dc` test, the clock from the receiver node is used. The `dc_clk` test derives its clock from the cable.

The following is an example of `sci` usage:

```
% sci 0 mb01 1 mb01 y dc_clk
```

This command runs the `dc_clk` test on the cable connected between node 0, memory board 1 (driver) and node 1, memory board 1 receiver.

---

## JTAG Identification test

The JTAG Identification test prints all JTAG IDs. the format is:

```
i
```

---

## Margin commands

The Margin command for clocks and power format is:

```
m [-c | -p [supply] [value]
```

The `-c` option specifies the clock, and the `-p` option specifies power.

When a value is not supplied, the current states are displayed.

By itself, `m` show all margins.

`-c high` displays the upper clock limit.

`-p 1 nom` sets the supply 1 margin to nominal.

---

## Miscellaneous commands

This section gives the following useful commands entered at the `est` prompt:

- `ms`—Puts all the scan hardware into a safe state
- `q`—Quit
- `script <file>`—Runs a file contain `est` commands
- `v`—Prints version information
- `F`—Opens the flags submenu

---

## Flags and options

There are flags and options that control how the tests operate. Entering `F` at the `est` prompt brings up the Flags submenu. Pressing `return` at the flags prompt returns to the main `est` prompt.

Some of the more useful flags and options are:

- **l**—Limits the number of internal array patterns that get executed by the **g** command. This has the affect of decreasing coverage to approximately 90%.
- **s**—Stops testing when an error is detected
- **A <number>**—Limits AC Connectivity testing
- **D <number>**—Limits DC Connectivity testing.
- **E**—Shows **sdp** packets transferred across the ethernet
- **P**—Controls whether or not the pass/fail status of individual patterns are displayed

---

## Script files

There are two ways of running script files: from the command line (**-f <filename>**) or from the **est** prompt. From the command line, **est** executes the instructions listed and when finished, displays the **est** prompt. To cause **est** to quit when the script is finished, put **q** at the end of the script file.

The **script** command reads **est** commands from an ASCII file and runs those commands. The following rules apply to the file:

- The file must have only one command per line.
- Command syntax must be the same as entered at the **est** prompt.
- Comments lines must start with a **#** sign.

An example file might contain the following lines:

```
check the rings
r
show pattern pass/fail steps
F P
#limit dc testing to 3 patterns
F D 3
#do dc testing
d
```

---

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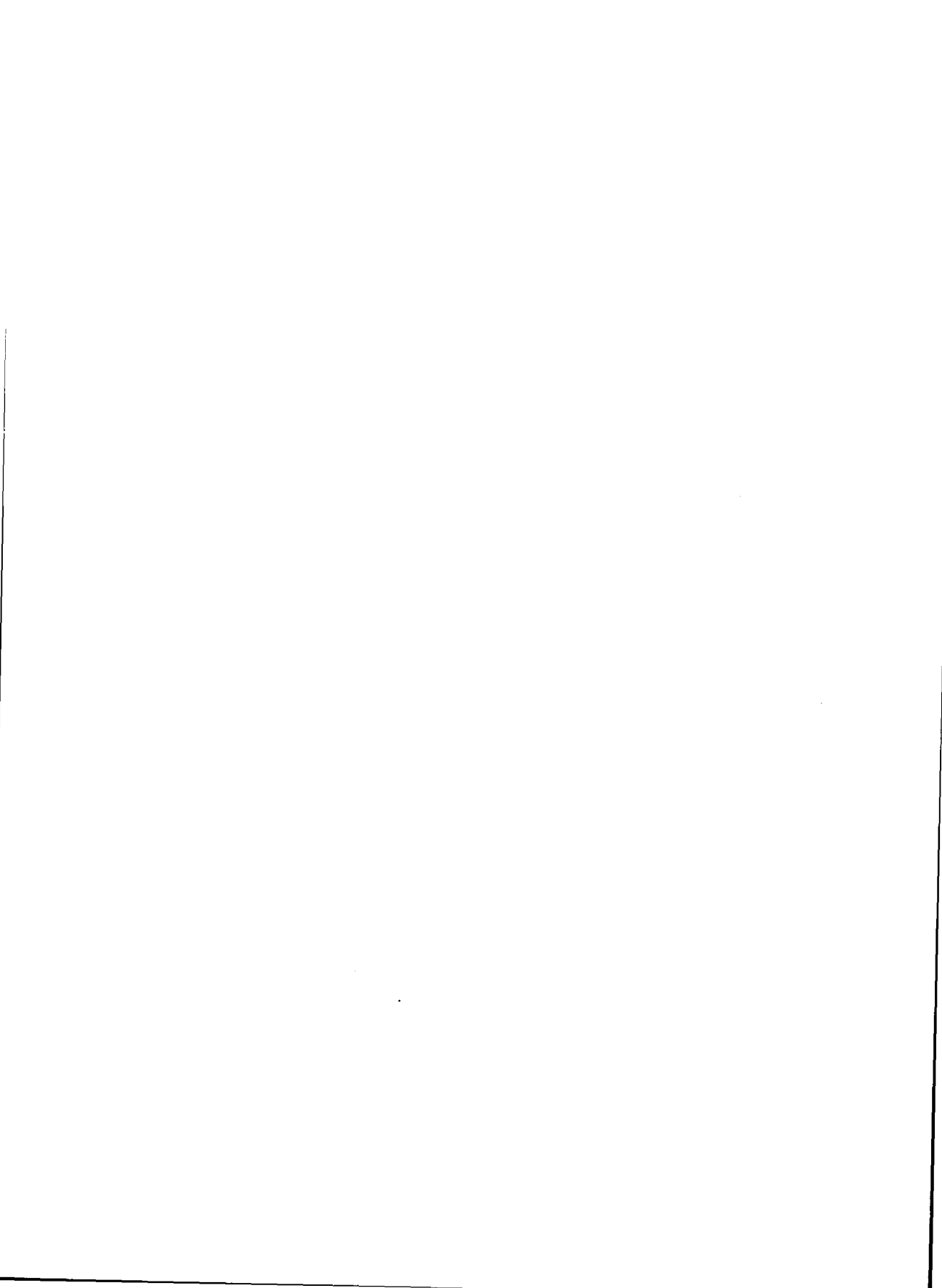
## V

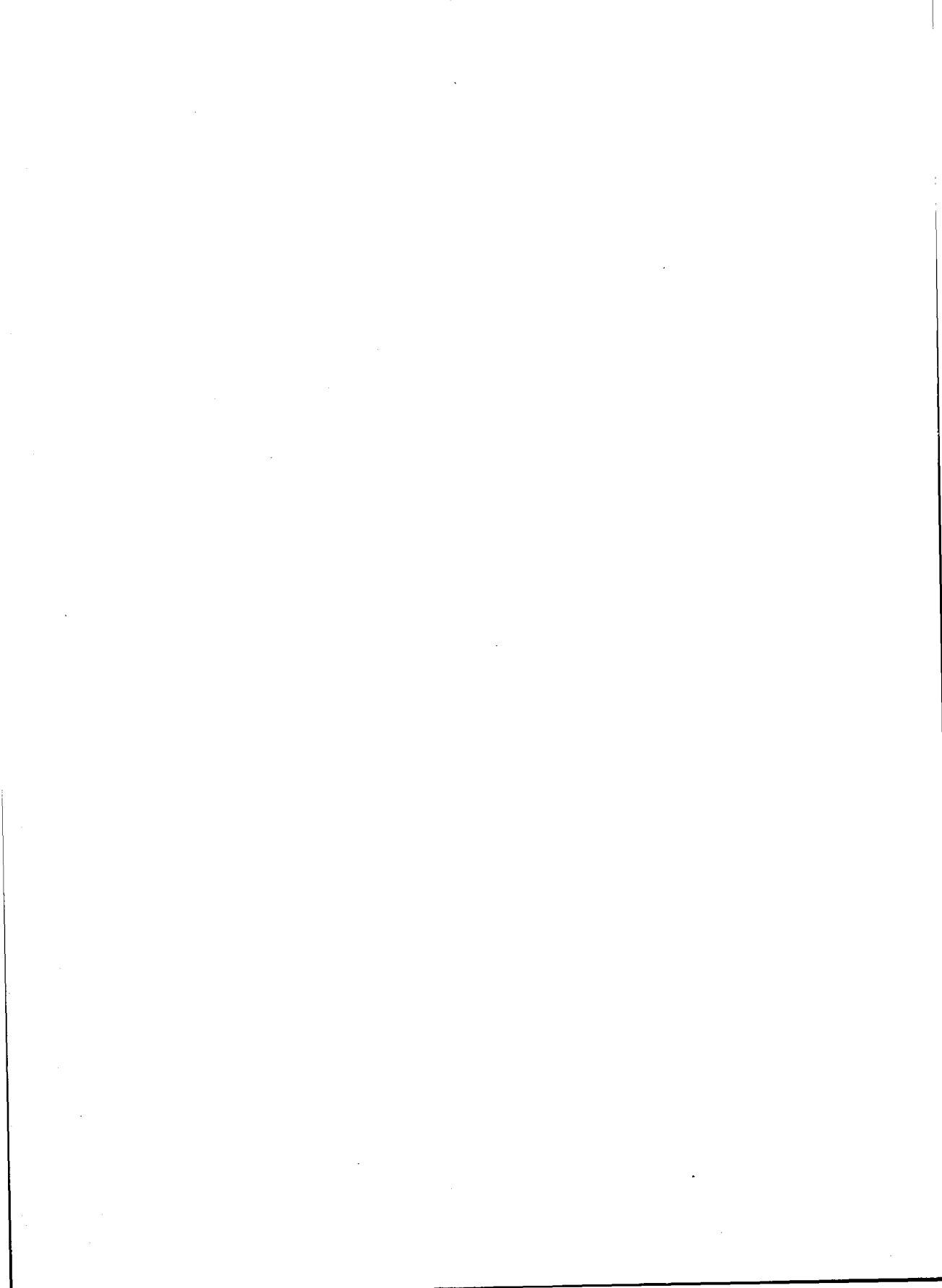
ver 93  
version utilities 92  
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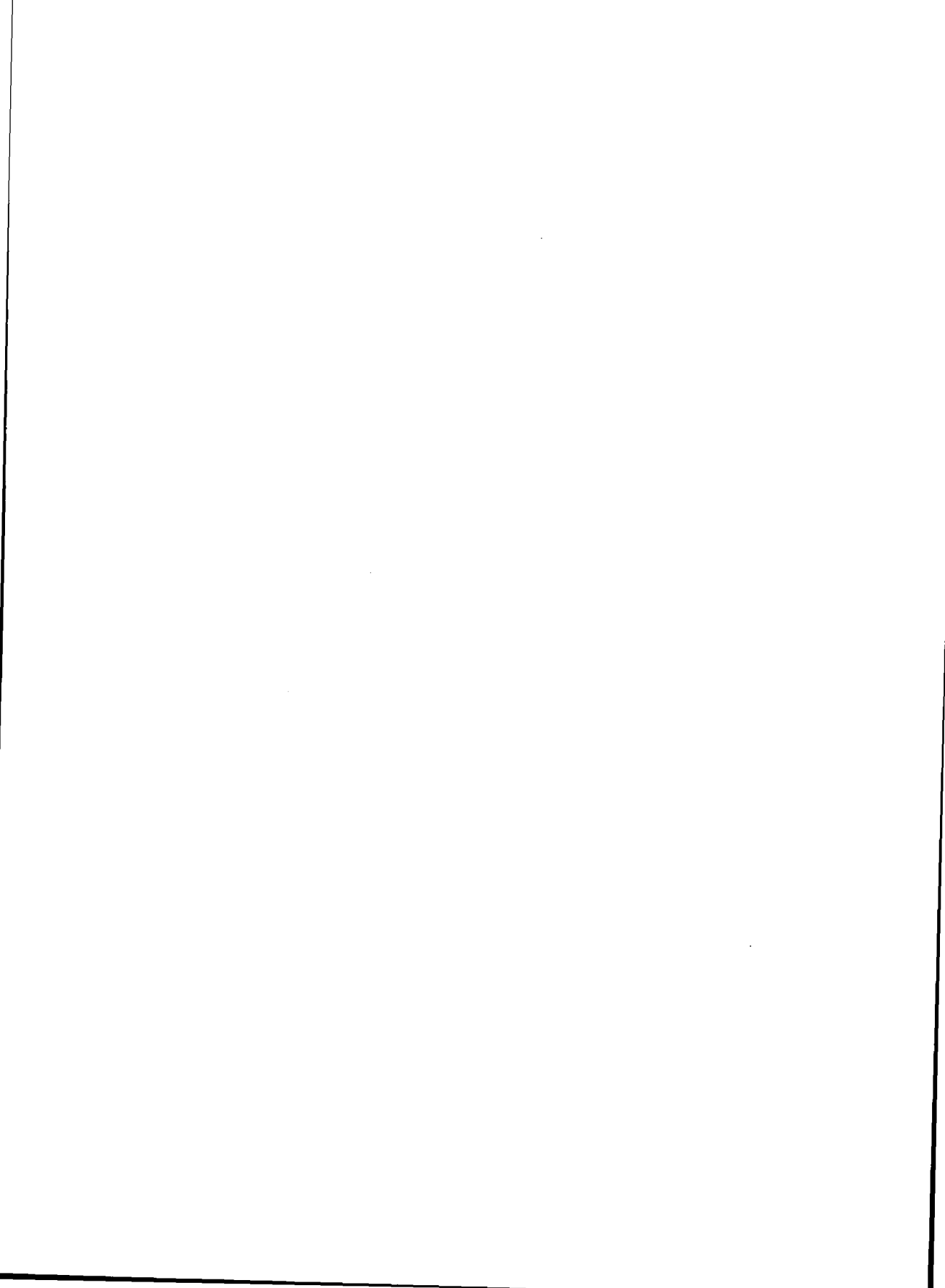
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